APRIL 30, 2009

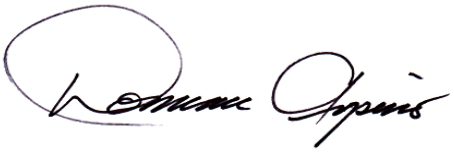
TEST REPORT #209145
REVISION 1.2

MIXED FLOWING GAS
TESTING

CONNECTOR PART NUMBERS

MEC8-120-02-C-DV-A
MEC8-170-02-C-DV-A

SAMTEC, INC.



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ATTLEBORO, MA

ilac-MRA

1478 - 01
ACCREDITED
Test Laboratory
1478 - 02

Contech Research
An Independent Test and Research Laboratory

REVISION HISTORY

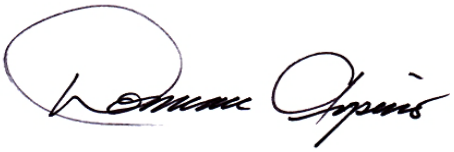
DATE	REV. NO.	DESCRIPTION	ENG.
4/30/2009	1.0	Initial Issue	DA
11/5/2010	1.1	Editorial changes on pages 6, 7 and on pages 32 through 82, removed references to “Sequence 2”. On page 31 removed reference to “Sequence 1”.	DA
12/02/2010	1.2	On page 6, corrected wording under first 7 days of MFG exposure from reading “unmated” to mated.	DA

CERTIFICATION

This is to certify that the evaluation described herein was designed and executed by personnel of Contech Research, Inc. It was performed with the concurrence of Samtec, Inc., of New Albany, IN who was the test sponsor.

All equipment and measuring instruments used during testing were calibrated and traceable to NIST according to ISO 10012-1 and ANSI/NCSL Z540-1 and MIL-STD-45662 as applicable.

All data, raw and summarized, analysis and conclusions presented herein are the property of the test sponsor. No copy of this report, except in full, shall be forwarded to any agency, customer, etc., without the written approval of the test sponsor and Contech Research.



Dominic Arpino
Project Engineering Manager
Contech Research, Inc.
Attleboro, MA

DA:ld

SCOPE

To perform Mixed Flowing Gas testing on MEC8 connector series as manufactured and submitted by the test sponsor Samtec, Inc.

APPLICABLE DOCUMENTS

1. Unless otherwise specified, the following documents of issue in effect at the time of testing performed form a part of this report to the extent as specified herein. The requirements of sub-tier specifications and/or standards apply only when specifically referenced in this report.

2. Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

1. The following test samples were submitted by the test sponsor, Samtec, Inc., for the evaluation to be performed by Contech Research, Inc.

TABLE 1

Connector P/N's	QTY
a) MEC8-170-01-C-DV-A 30 Au	8
b) MEC8-120-01-C-DV-A 30 Au	8
c) MEC8-170-01-C-DV-A 50 Au	8
d) MEC8-120-01-C-DV-A 50 Au	8

2. Test samples were supplied assembled and terminated to test boards by the test sponsor.

3. The test samples were tested in their 'as received' condition.

4. Stabilizing mediums were assembled to each test sample to maintain stability between the mated pair.

5. Unless otherwise specified in the test procedures used, no further preparation was used.

TEST SELECTION

1. See Test Plan Flow Diagram, Figure #1, for test sequences used.

TEST SELECTION -continued

2. Test set ups and/or procedures which are standard or common are not detailed or documented herein provided they are certified as being performed in accordance with the applicable (industry or military) test methods, standards and/or drawings as specified in the detail specification.

SAMPLE CODING

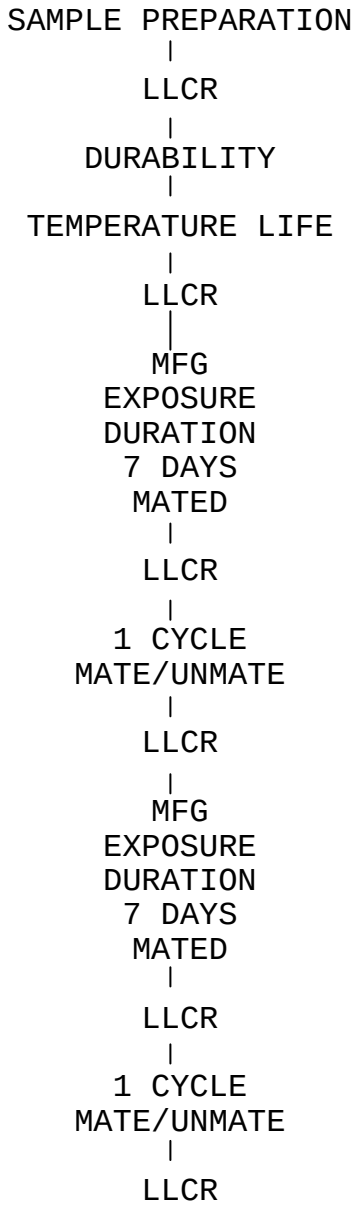
1. All samples were coded. Mated test samples remained with each other throughout the test group/sequences for which they were designated. Coding was performed in a manner which remained legible for the test duration.

2. The test samples were coded in the following manner:

PART NUMBERS	**FILE ID#'S**
MEC8-170-01-C-DV-A (30 Au)	20914501 to 20914508
MEC8-120-01-C-DV-A (30 Au)	20914509 to 20914516
MEC8-170-01-C-DV-A 50 Au	20914517 to 20914524
MEC8-120-01-C-DV-A 50 Au	20914525 to 20914532

FIGURE #1

TEST PLAN FLOW DIAGRAM



DATA SUMMARY

TEST	REQUIREMENT	RESULT
LLCR		
MEC8-170-01-C-DV-A 30Au	RECORD	15.6 mΩ MAX.
MEC8-120-01-C-DV-A 30Au	RECORD	17.6 mΩ MAX.
MEC8-170-01-C-DV-A 50Au	RECORD	15.4 mΩ MAX.
MEC8-120-01-C-DV-A 50Au	RECORD	16.6 mΩ MAX.
DURABILITY		
MEC8-170-01-C-DV-A 30Au	NO DAMAGE	PASSED
MEC8-120-01-C-DV-A 30Au	NO DAMAGE	PASSED
MEC8-170-01-C-DV-A 50Au	NO DAMAGE	PASSED
MEC8-120-01-C-DV-A 50Au	NO DAMAGE	PASSED
TEMPERATURE LIFE		
MEC8-170-01-C-DV-A 30Au	NO DAMAGE	PASSED
MEC8-120-01-C-DV-A 30Au	NO DAMAGE	PASSED
MEC8-170-01-C-DV-A 50Au	NO DAMAGE	PASSED
MEC8-120-01-C-DV-A 50Au	NO DAMAGE	PASSED
LLCR		
MEC8-170-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+0.3 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+0.8 mΩ MAX.CHG.
MEC8-170-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+0.4 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+0.5 mΩ MAX.CHG.
MFG –MATED		
MEC8-170-01-C-DV-A 30Au	EXPOSE MATED	PASSED
MEC8-120-01-C-DV-A 30Au	EXPOSE MATED	PASSED
MEC8-170-01-C-DV-A 50Au	EXPOSE MATED	PASSED
MEC8-120-01-C-DV-A 50Au	EXPOSE MATED	PASSED
LLCR		
MEC8-170-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+0.4 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+0.6 mΩ MAX.CHG.
MEC8-170-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+0.3 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+1.2 mΩ MAX.CHG.

DATA SUMMARY -continued

MFG – MATED		
MEC8-170-01-C-DV-A 30Au	EXPOSE MATED	PASSED
MEC8-120-01-C-DV-A 30Au	EXPOSE MATED	PASSED
MEC8-170-01-C-DV-A 50Au	EXPOSE MATED	PASSED
MEC8-120-01-C-DV-A 50Au	EXPOSE MATED	PASSED
LLCR		
MEC8-170-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+0.7 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+0.8 mΩ MAX.CHG.
MEC8-170-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+0.6 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+3.3 mΩ MAX.CHG.
1 CYCLE		
MEC8-170-01-C-DV-A 30Au	NO DAMAGE	PASSED
MEC8-120-01-C-DV-A 30Au	NO DAMAGE	PASSED
MEC8-170-01-C-DV-A 50Au	NO DAMAGE	PASSED
MEC8-120-01-C-DV-A 50Au	NO DAMAGE	PASSED
LLCR		
MEC8-170-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+4.3 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 30Au	+10.0 mΩ MAX.CHG.	+3.8 mΩ MAX.CHG.
MEC8-170-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+2.8 mΩ MAX.CHG.
MEC8-120-01-C-DV-A 50Au	+10.0 mΩ MAX.CHG.	+2.4 mΩ MAX.CHG.

EQUIPMENT LIST

ID#	Next Cal	Last Cal	Equipment Name	Manufacturer	Model #	Serial #	Accuracy	Freq.Cal
102	2/27/2010	2/27/2009	Data Acquisition Unit	Hewlett Packard	3421A	2338A02027	±. 5 %Of Indicated	12mon
152			Drill Press Stand	Craftsman	25921	N/A	N/A	N/A
207	12/9/2009	12/9/2008	Micro-Ohm Meter	Keithley Co.	580	438208	See Cal Cert	12mon
244	9/22/2009	9/22/2008	Micro-Ohm Meter	Keithley Instr.	580-1	467496	See Cal Cert	12mon
270			MFG Chamber	Contech Research	5 Cu Ft	N/A	N/A	Ea Test
297	11/13/2009	11/13/2008	Micro-Ohm Meter	Keithley Instr.	580	485414	See Cal Cert	12mon
323			Computer	Legatech	286-12	N/A	N/A	N/A
436			Gas Regulator	Liquid Carboinc Co.	702-S-3	392838	N/A	N/A
443			Gas Regulator Valve	Liquid Carbonic Co.	DRK-2-48	40197	See Manual	N/A
476			Computer	Twilight Co.	386-33	N/A	N/A	N/A
510			Regulator	Liquid Carbonic	SGS 160C	M2 42366	N/A	N/A
512			Bench Oven	Blue M Co.	POM 146C-1	CD9506	See Manual	Ea Test
525			Gas Regulator	Superior Co.	5113A	350218	See Owners Manual	N/A
527	10/24/2009	10/24/2008	Digital Thermometer	Omega Co.	DP116	4301400	±1.1DegC	12mon
543	12/3/2009	12/3/2008	Analytical Balance	Ohaus Co.	AP250D	MO9198	± .4mg	12mon
1027			Computer	ARC Co.	Pent.133	026871	N/A	N/A
1032			Computer	Magitronic	486DX4	100VL	N/A	N/A
1047	12/10/2009	12/10/2008	Microohm Meter	Keithley	580	0705731	See Cal Cert	12mon
1110			Elect.Liquid Level Cntrl	Cole Parmer	7187	15986	N/A	N/A
1116			Computer	ARC. Co.	P111-450		N/A	N/A
1276			Computer	ARC.Co.	Pent-450	N/A	N/A	N/A
1296			MFG Control Panel	Contech Research	N/A	N/A	N/A	N/A
1324			X-Y Table	Contech Research	CR-XY	03	N/A	N/A
1381			Air Dryer	Balston	75-20	A03391	See Manual	N/A
1507	4/6/2010	4/6/2009	Temp Humid Transmitter	Vaisala	HMT333	C1110019	See Cal Cert	12mon
1546	1/8/2010	1/8/2009	Microohm meter	Keithley	580	0803454	See Cert	12mon
1595			H2S Analyzer	Teledyne Analyzer	101-E	1231	See Manual	Ea Test
1599			NO2 Analyzer	Teledyne Analyzer	200E	289	See cert	12mon

TEST RESULTS

GROUP A

PROJECT NO.: 209145	SPECIFICATION: EIA-364-23
PART NO.: See page 4	PART DESCRIPTION: See page 4
SAMPLE SIZE: 32 connectors	TECHNICIAN: LL, DAM, AJP, BE, S.Rath, MHB
START DATE: 3/16/09	COMPLETE DATE: 3/16/09
ROOM AMBIENT: 22°C	RELATIVE HUMIDITY: 27%
EQUIPMENT ID#: 207, 244, 297, 323, 476, 1032, 1047, 1116, 1276, 1546	

LOW LEVEL CIRCUIT RESISTANCE (LLCR)

PURPOSE:

1. To evaluate contact resistance characteristics of the contact systems under conditions where applied voltages and currents do not alter the physical contact interface and will detect oxides and films which degrade electrical stability. It is also sensitive to and may detect the presence of fretting corrosion induced by mechanical or thermal environments as well as any significant loss of contact pressure.

2. This attribute was monitored after each preconditioning and/or test exposure in order to determine said stability of the contact systems as they progress through the applicable test sequences.

3. The electrical stability of the system is determined by comparing the initial resistance value to that observed after a given test exposure. The difference is the change in resistance occurring whose magnitude establishes the stability of the interface being evaluated.

PROCEDURE:

1. The test was performed in accordance with EIA 364, Test Procedure 23 with the following conditions.

-continued on next page.

PROCEDURE: -continued

2. Test Conditions:

a) Test Current : 100 milliamps maximum
b) Open Circuit Voltage : 20 millivolts
c) No. of Positions Tested : 25 per test sample

REQUIREMENTS:

Low level circuit resistance shall be measured and recorded.

RESULTS:

1. The following is a summary of the data observed:

	LOW LEVEL CIRCUIT RESISTANCE (milliohms)		
Sample ID#	Avg.	Max.	Min.
MEC8-170-01-C-DV-A 30 Au			
1	13.9	14.6	13.2
2	13.9	15.4	13.2
3	14.1	15.3	13.3
4	14.2	15.4	13.6
5	13.9	15.0	12.8
6	14.0	15.1	13.0
7	14.4	15.4	13.7
8	14.5	15.6	13.8

	LOW LEVEL CIRCUIT RESISTANCE (milliohms)		
Sample ID#	Avg.	Max.	Min.
MEC8-170-01-C-DV-A 50 Au			
9	14.9	15.4	14.5
10	14.2	15.2	13.4
11	14.4	14.7	14.0
12	14.7	15.2	14.2
13	14.4	14.9	13.9
14	14.0	14.7	13.3
15	14.2	14.6	13.9
16	14.5	15.1	14.0

-continued on next page.

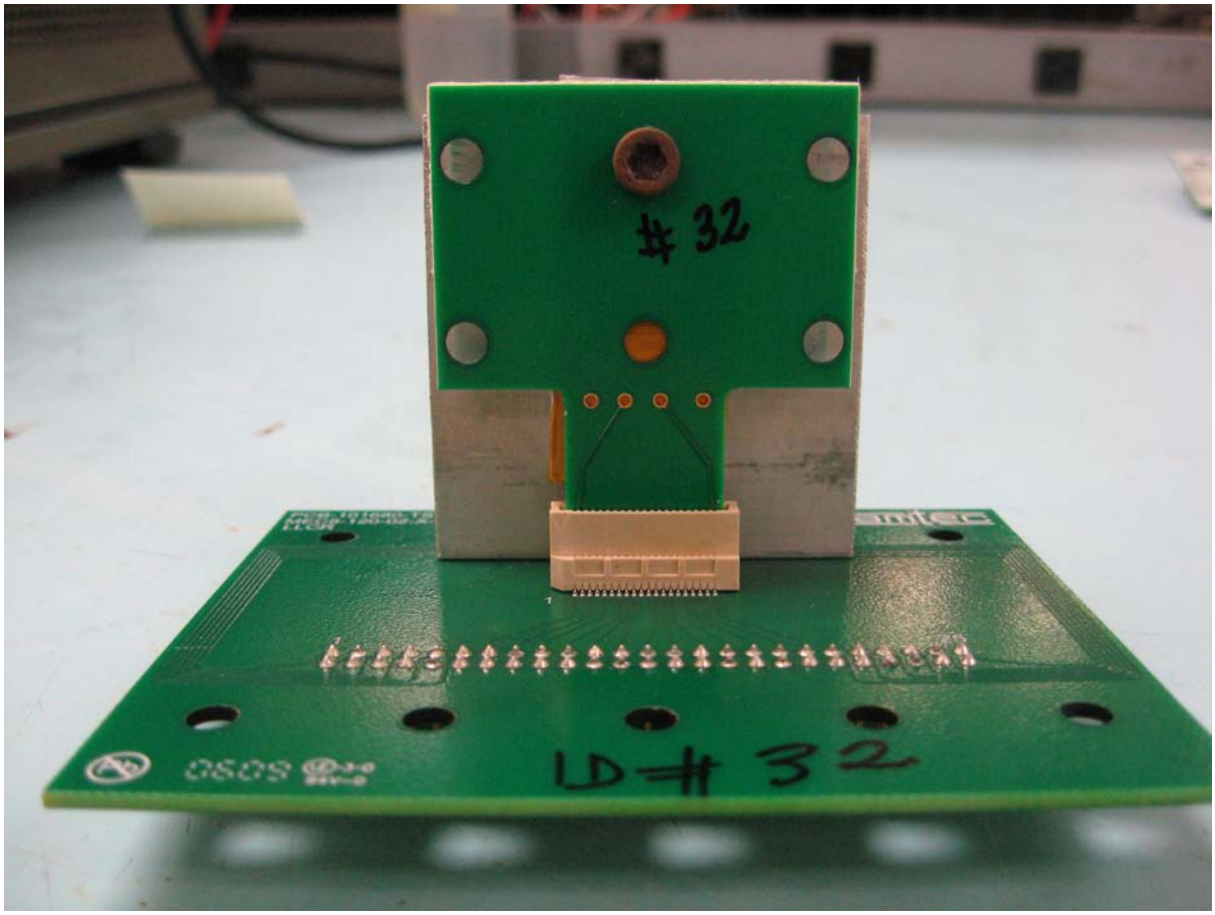
RESULTS: -continued

Sample ID#	LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg.	Max.	Min.
MEC8-120-01-C-DV-A 30 Au			
17	15.0	17.6	14.1
18	14.2	14.4	13.9
19	14.8	15.1	14.5
20	14.2	14.7	13.8
21	14.1	14.4	13.7
22	14.9	17.5	14.1
23	14.6	15.1	14.1
24	14.0	14.3	13.8

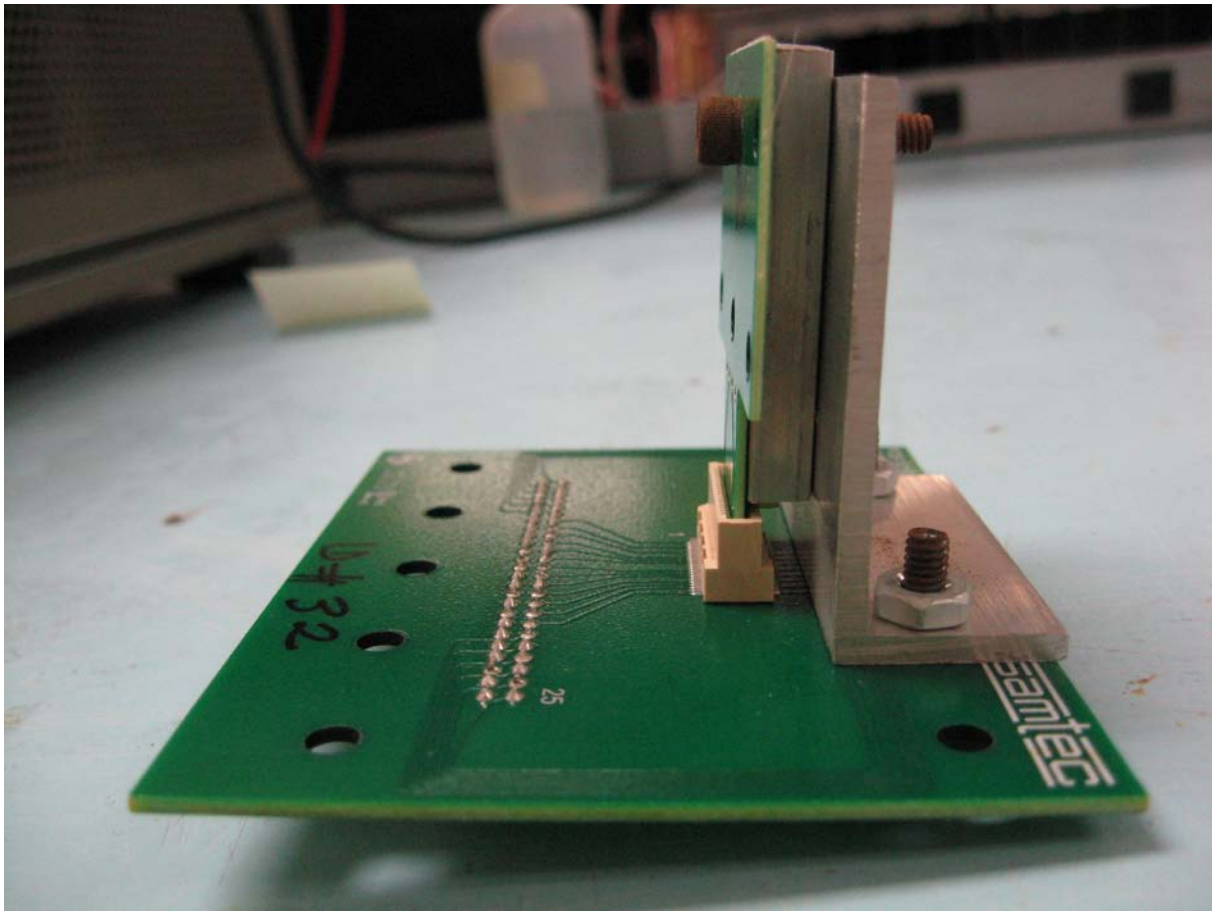
Sample ID#	LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg.	Max.	Min.
MEC8-120-01-C-DV-A 50 Au			
25	13.7	14.3	13.4
26	14.1	15.0	13.3
27	14.3	15.6	13.2
28	14.1	15.5	13.1
29	14.1	16.6	13.4
30	14.0	15.1	13.3
31	13.7	14.2	13.2
32	13.8	14.6	13.0

2. See the attached data files for individual data points.

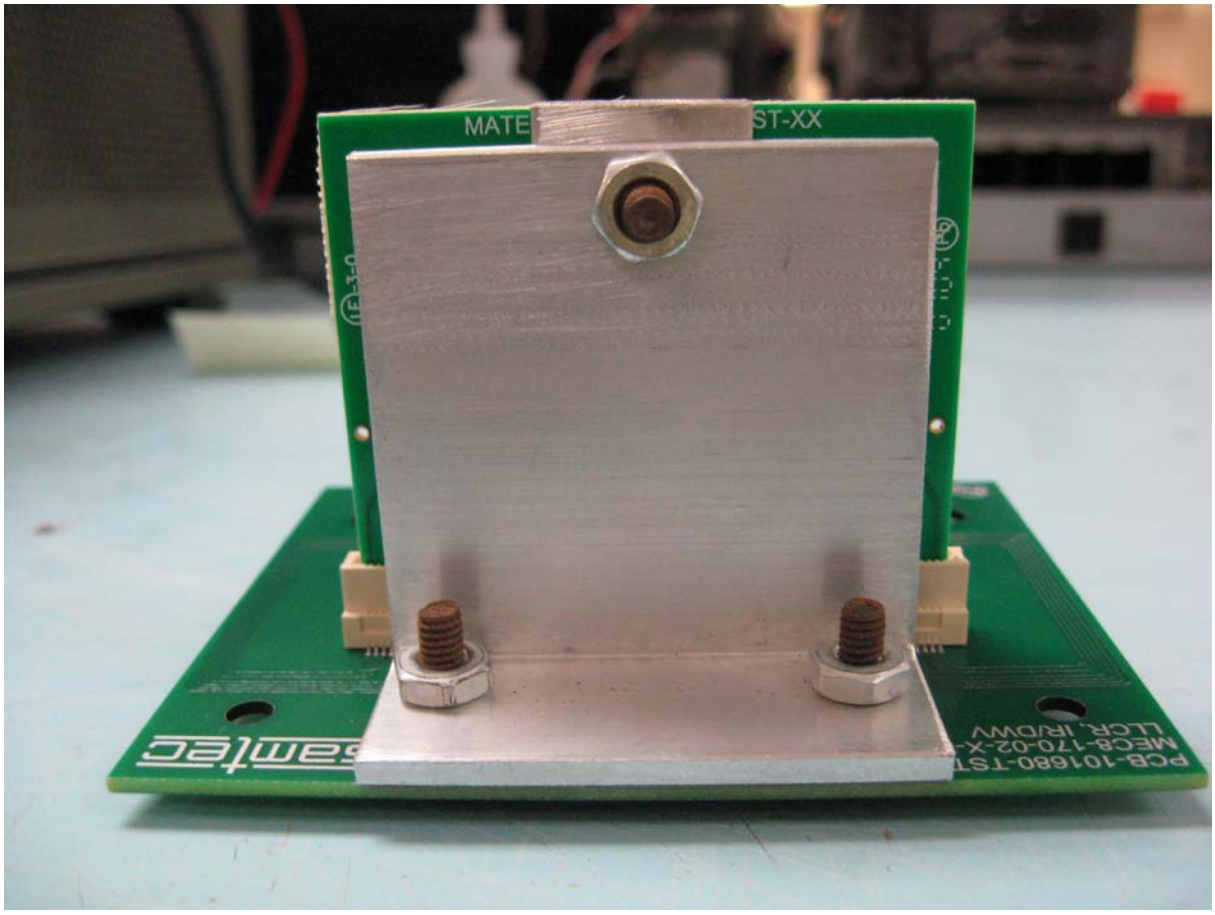
FRONT VIEW OF THE MECA-120-01-C-DV-A CONNECTOR



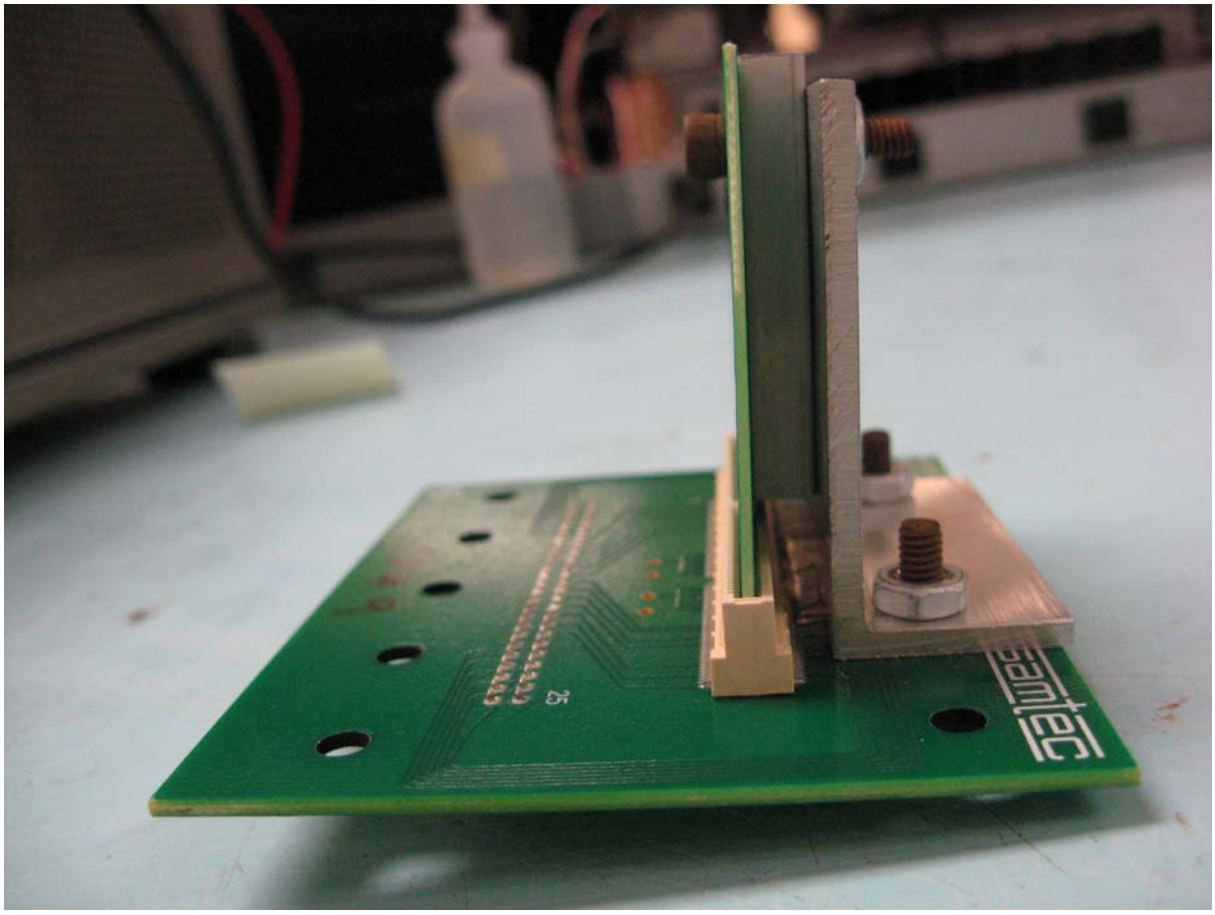
SIDE VIEW OF THE MECA-120-01-C-DV-A CONNECTOR



REAR VIEW OF THE MECA-170-01-C-DV-A CONNECTOR



SIDE VIEW OF THE MECA-170-01-C-DV-A CONNECTOR



PROJECT NO.: 209145	SPECIFICATION: EIA-364-09
PART NO.: See page 4	PART DESCRIPTION: See page 4
SAMPLE SIZE: 32 connectors	TECHNICIAN: DAM
START DATE: 3/17/09	COMPLETE DATE: 3/17/09
ROOM AMBIENT: 22°C	RELATIVE HUMIDITY: 24%
EQUIPMENT ID#: 152,1324	

DURABILITY

PURPOSE:

1. This is a preconditioning sequence which is used to induce the type of wear on the contacting surfaces which may occur under normal service conditions. The connectors are mated and unmated a predetermined number of cycles. Upon completion, the units being evaluated are exposed to the environments as specified to assess any impact on electrical stability resulting from wear or other wear dependent phenomenon.

2. This type or preconditioning sequence is also used to mechanically stress the connector system as would normally occur in actual service. This sequence in conjunction with other tests is used to determine if a significant loss of contact pressure occurs from said stresses which in turn, may result in an unstable electrical condition to exist.

PROCEDURE:

1. The test was performed in accordance with EIA 364, Test Procedure 09.

2. Test Conditions:

    a) No. of Cycles : 5X
    b) Rate : 1.0 inch per minute

2. The samples were cycled using an X Y Table and a drill press stand.

-continued on next page.

PROCEDURE: -continued

4. All subsequent variable testing was performed in accordance with the procedures previously indicated.

REQUIREMENTS:

There shall be no evidence of physical damage to the test samples so tested.

RESULTS:

There was no evidence of physical damage to the test samples so tested.

PROJECT NO.: 209145	SPECIFICATION: EIA-364-17
PART NO.: See page 4	PART DESCRIPTION: See page 4
SAMPLE SIZE: 32 connectors	TECHNICIAN: DAM
START DATE: 3/18/09	COMPLETE DATE: 4/2/09
ROOM AMBIENT: 22°C	RELATIVE HUMIDITY: 25%
EQUIPMENT ID#: 512, 527	

TEMPERATURE LIFE

PURPOSE:

To evaluate the mechanical stability of the contact systems when exposed to a thermal environment. Said environment may generate temperature dependent failure mechanisms such as:

a) Dry oxidation of base metals and/or underplates which have reached the contacting surfaces by impurity, diffusion or pore corrosion.

b) Dry oxidation due to smearing of base metal and/or underplate on the contact surfaces or exposure of same due to wear.

c) Reduced normal (contact) force due to stress relaxation as a result of a thermal environment.

PROCEDURE:

1. The test samples were placed in the test chamber after it had reached equilibrium at the specified temperature level. The test exposure was performed in accordance with EIA 364, Test Procedure 17, with the following conditions.

2. Test Condition:

a) Temperature : 90°C ± 2°C
b) Duration : 360 hours
c) Mated Condition : Mated
d) Mounting Condition : Mounted

-continued on next page.

PROCEDURE: -continued

3. Prior to any measurements, test samples were removed from the chamber and allowed to cool to room ambient for 2 hours.

4. After recovery to room ambient conditions, the low level contact resistance was measured and recorded.

5. All subsequent variable testing was performed in accordance with the procedures previously indicated.

REQUIREMENTS:

1. There shall be no evidence of physical damage or deterioration of the test samples so exposed.

2. The change in low level circuit resistance shall not exceed +10.0 milliohms.

RESULTS:

1. The following is a summary of the data observed:

	CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms)	
Sample ID#	Avg. Change	Max. Change
MEC8-170-01-C-DV-A 30 Au		
1	-0.5	+0.2
2	-0.6	+0.3
3	-0.6	-0.2
4	-0.7	-0.1
5	-0.5	+0.3
6	-0.6	+0.0
7	-0.6	+0.2
8	-0.7	+0.1

-continued on next page.

RESULTS: -continued

Sample ID#	CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change	Max. Change
MEC8-170-01-C-DV-A 50 Au		
9	-0.3	+0.2
10	-0.7	-0.2
11	-0.3	-0.1
12	-0.6	+0.4
13	-0.3	+0.3
14	-0.5	+0.0
15	-0.3	+0.1
16	-0.4	+0.1

Sample ID#	CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change	Max. Change
MEC8-120-01-C-DV-A 30 Au		
17	-0.1	+0.8
18	-0.2	+0.6
19	-0.5	-0.1
20	-0.2	+0.2
21	-0.5	-0.1
22	-0.7	+0.1
23	-0.2	+0.1
24	-0.1	+0.1

-continued on next page.

RESULTS: -continued

Sample ID#	CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change	Max. Change
MEC8-120-01-C-DV-A 50 Au		
25	-0.3	+0.1
26	-0.9	+0.0
27	-0.4	+0.5
28	-0.8	+0.3
29	-0.8	-0.2
30	-0.9	-0.2
31	-0.2	+0.1
32	-0.6	+0.3

2. See the attached data files for individual data points.

PROJECT NO.: 209145 SPECIFICATION: EIA-364-65

PART NO.: See page 4 PART DESCRIPTION: See page 4

SAMPLE SIZE: 32 connectors TECHNICIAN: WJC

START DATE: 4/6/09 COMPLETE DATE: 4/21/09

ROOM AMBIENT: 21°C RELATIVE HUMIDITY: 48%

EQUIPMENT ID#: 102, 270, 436, 443, 510, 525, 543, 1027, 1110
1296, 1381, 1507, 1571, 1595, 1599

MIXED FLOWING GAS

PURPOSE:

1. To determine the impact on electrical stability of contact interfaces when the test samples are exposed to a mixed flowing gas environment. Said environment is based on field data simulating typical, severe, non-benign environments. Said exposure is indicative of expected behavior in the field.

2. Mixed flowing gas tests (MFG) are environmental test procedures whose primary purpose is to evaluate product performance under simulated storage or operating (field) conditions. For parts involving plated contact surfaces, such tests are also used to measure the effect of plating degradation (due to the environment) on the electrical and durability properties of a contact or connector system. The specific test conditions are usually chosen so as to simulate, in the test laboratory, the effects of certain representative field environments or environmental severity levels on standard metallic surfaces.

PROCEDURE:

1. The test environment was performed in accordance with EIA 364, Test Procedure 65 with the following conditions.

-continued on next page.

PROCEDURE: -continued

2. Environmental Conditions:

a) Temperature	:	30°C ± 1°C
b) Relative Humidity	:	70% ± 2%
c) $C1_2$	:	10 ± 3 ppb
d) NO_2	:	200 ± 50 ppb
e) H_2S	:	10 ± 5 ppb
f) SO_2	:	100 ± 20 ppb
g) Exposure Time	:	14 days
h) Mating Conditions	:	First 7 days - mated Second 7 days -mated

3. The test chamber was allowed to stabilize at the specified conditions indicated.

4. After stabilization, the test samples and control coupons were placed in the chamber such that they were no closer than 2.0" from each other and/or the chamber walls.

5. The test samples were handled in a manner so as not to disturb the contact interface.

6. After placement of the test samples in the chamber, it was allowed to re-stabilize and adjusted as required to maintain the specified concentrations and conditions.

7. The test chamber was monitored periodically during the exposure period to assure the environmental conditions as specified were maintained.

8. All subsequent variable testing was performed in accordance with the procedures previously indicated.

REQUIREMENTS:

1. There shall be no evidence of damage or corrosion to the test samples as exposed which will cause mechanical or electrical malfunction of the said samples.

2. The change in low level circuit resistance shall not exceed +10.0 milliohms.

RESULTS: See Next Page

RESULTS:

1. The following is a summary of the data observed following the 7 and 14 days mated portion of the exposure:

Sample ID#	MAXIMUM CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change @ 7 Days	Max. Change @ 7 Days	Avg. Change @14 Days	Max. Change @14 Days
MEC8-170-01-C-DV-A 30 Au				
1	-0.5	+0.3	-0.5	+0.1
2	-0.5	+0.4	-0.6	+0.1
3	-0.5	+0.1	-0.6	-0.2
4	-0.6	-0.1	-1.0	+0.0
5	-0.5	+0.4	-0.6	+0.2
6	-0.5	+0.1	-0.8	+0.7
7	-0.5	+0.3	-0.9	-0.3
8	-0.5	+0.1	-0.7	-0.1

Sample ID#	MAXIMUM CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change @ 7 Days	Max. Change @ 7 Days	Avg. Change @14 Days	Max. Change @14 Days
MEC8-170-01-C-DV-A 50 Au				
9	-0.3	+0.0	-0.5	-0.1
10	-0.6	-0.1	-0.7	-0.3
11	-0.2	+0.2	-0.3	+0.6
12	-0.5	+0.1	-0.7	-0.1
13	-0.3	+0.1	-0.5	+0.0
14	-0.4	-0.1	-0.2	+0.1
15	-0.2	+0.2	-0.2	+0.3
16	-0.2	+0.3	-0.2	+0.6

-continued on next page.

RESULTS: -continued

MAXIMUM CHANGE IN
LOW LEVEL CIRCUIT RESISTANCE
(milliohms)

Sample ID#	Avg. Change @ 7 Days	Max. Change @ 7 Days	Avg. Change @ 14 Days	Max. Change @ 14 Days
MEC8-120-01-C-DV-A 30 Au				
17	-0.1	+0.4	-0.2	+0.5
18	-0.2	+0.0	-0.2	+0.1
19	-0.4	-0.2	-0.1	+0.8
20	-0.2	+0.2	-0.3	+0.3
21	-0.3	+0.1	-0.3	+0.2
22	-0.7	+0.1	-0.6	-0.1
23	-0.2	+0.1	-0.3	+0.0
24	+0.1	+0.6	-0.1	+0.2

MAXIMUM CHANGE IN
LOW LEVEL CIRCUIT RESISTANCE
(Milliohms)

Sample ID#	Avg. Change @ 7 Days	Max. Change @ 7 Days	Avg. Change @ 14 Days	Max. Change @ 14 Days
MEC8-120-01-C-DV-A 50 Au				
25	-0.3	+0.0	-0.1	+3.3
26	-0.8	-0.1	-0.6	+0.5
27	-0.7	+0.1	-0.5	+0.4
28	-0.6	+0.1	-0.9	-0.1
29	-0.2	+1.2	-0.5	+0.3
30	-0.7	-0.2	-0.7	+0.1
31	-0.3	+0.0	-0.4	+0.0
32	-0.6	+0.2	-0.3	+0.4

-continued on next page.

RESULTS: -continued

2. The following is a summary of the data observed following reseating; manually unmate and remate one time after the MFG exposure.

Sample ID#	MAXIMUM CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change	Max. Change
MEC8-170-01-C-DV-A 30 Au		
	1 Cycle	
1	+0.2	+0.6
2	+0.0	+0.6
3	+0.1	+1.1
4	+0.1	+0.9
5	+0.6	+1.5
6	-0.1	+0.7
7	+1.1	+4.3
8	+0.2	+1.9

Sample ID#	MAXIMUM CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change	Max. Change
MEC8-170-01-C-DV-A 50 Au		
	1 Cycle	
9	+0.0	+0.8
10	+0.1	+1.6
11	+0.4	+2.8
12	-0.1	+0.7
13	+0.0	+1.2
14	+0.1	+2.2
15	+0.6	+2.1
16	+0.8	+2.5

-continued on next page.

RESULTS: -continued

Sample ID#	MAXIMUM CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change	Max. Change
MEC8-120-01-C-DV-A 30 Au		
	1 Cycle	
17	+0.3	+2.1
18	-0.1	+0.2
19	-0.2	+0.4
20	+0.6	+3.8
21	+0.1	+0.6
22	-0.4	+1.0
23	+0.0	+0.5
24	+0.1	+0.6

Sample ID#	MAXIMUM CHANGE IN LOW LEVEL CIRCUIT RESISTANCE (milliohms) Avg. Change	Max. Change
MEC8-120-01-C-DV-A 50 Au		
	1 Cycle	
25	+0.4	+1.3
26	+0.2	+2.4
27	+0.4	+1.2
28	-0.2	+0.5
29	+0.2	+1.3
30	+0.4	+1.5
31	+0.4	+1.7
32	-0.2	+0.6

3. See the attached data files for individual data points.

-continued on next page.

RESULTS: -continued

4. Five copper coupons were placed in the chamber. Upon removal said coupons were evaluated via weight gain technique with the following results:

	WEIGHT GAIN ($\mu gm/cm^2/Day$)	
Coupon No.	Mated	Mated
1	13	14
2	14	14+
3	12+	13
4	13	12+
5	15	13

Requirement: 12 to 16 $\mu gm/cm^2/Day$

LLCR DATA FILES

FILE NUMBERS

MEC8-170-01-C-DV-A 30 Au

20914501
20914502
20914503
20914504
20914505
20914506
20914507
20914508

Low Level Contact Resistance						
Project:	209145				Spec: EIA 364, TP23	
Customer:	Samtec				Subgroup: N/A	
Product:	MEC8-170-01-C-DV-A				File #: 20914501	
Description:	30 Au				Sample ID: 1	
Open circuit voltage:		20mv			Current: 100ma	
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.5	-0.5	-0.4	-0.4	0.4	
2	13.5	-0.5	-0.4	-0.4	-0.2	
3	13.6	-0.2	0.3	-0.3	0.6	
4	13.6	0.0	-0.1	-0.2	0.2	
5	13.9	-0.4	-0.5	-0.7	0.4	
6	13.4	0.2	0.1	-0.5	-0.1	
7	14.4	-1.2	-1.0	-1.0	-0.5	
8	14.5	-1.2	-1.1	-0.7	0.1	
9	13.8	-0.6	-0.5	-0.2	-0.2	
10	13.8	-0.4	-0.3	-0.3	0.1	
11	13.5	-0.4	-0.3	-0.3	0.2	
12	13.8	-0.5	-0.5	-0.4	0.4	
13	14.0	-0.6	-0.6	-0.4	-0.1	
14	14.6	-0.9	-1.0	-1.1	-0.5	
15	14.1	-0.5	-0.6	-0.7	-0.1	
16	14.4	-1.0	-1.0	-1.1	-0.1	
17	14.3	-1.1	-1.0	-1.1	0.0	
18	14.3	-1.0	-1.0	-1.1	0.3	
19	14.4	-0.5	-0.4	-0.4	0.5	
20	13.2	0.2	-0.5	0.1	0.5	
21	13.5	-0.1	-0.7	-0.1	0.1	
22	13.5	0.0	-0.1	-0.2	0.5	
23	13.7	-0.1	-0.1	-0.2	0.5	
24	13.3	0.1	0.1	-0.1	0.1	
25	13.8	-0.1	0.0	-0.2	0.6	

					File #: 20914501	
			Delta values			
			units: milliohms			
MAX	14.6	0.2	0.3	0.1	0.6	
MIN	13.2	-1.2	-1.1	-1.1	-0.5	
AVG	13.9	-0.5	-0.5	-0.5	0.2	
STD	0.4	0.4	0.4	0.4	0.3	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A				File #:	20914502
Description:	30 Au				Sample ID:	2
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.7	-0.6	-0.6	-0.8	0.5	
2	13.2	-0.3	-0.2	-0.4	0.3	
3	13.2	-0.4	-0.1	-0.3	0.6	
4	13.9	-0.6	-0.2	-0.4	0.4	
5	13.2	-0.2	0.1	-0.1	0.6	
6	13.2	-0.3	0.1	-0.3	0.4	
7	13.8	-0.2	-0.3	-0.4	0.3	
8	13.8	-0.3	-0.6	-0.4	0.3	
9	14.2	-0.2	-0.2	-0.4	0.6	
10	15.2	-1.4	-1.4	-1.5	0.1	
11	14.1	-0.3	-0.1	-0.2	0.4	
12	13.6	-0.5	-0.4	-0.5	0.4	
13	14.9	-1.1	-0.9	-0.9	-1.1	
14	14.5	-1.1	-0.8	-1.0	0.0	
15	14.2	-0.6	-0.4	-0.5	-0.3	
16	15.4	-2.0	-1.9	-2.0	-2.1	
17	14.7	-1.3	-1.2	-1.3	0.1	
18	13.7	0.3	0.4	0.1	0.3	
19	14.3	-0.9	-0.8	-1.0	-0.9	
20	13.3	-0.3	-0.5	-0.4	-0.2	
21	13.3	-0.3	-0.3	-0.3	0.0	
22	13.3	-0.6	-0.7	-0.6	-0.2	
23	13.2	-0.6	-0.6	-0.5	-0.3	
24	13.6	-0.7	-0.7	-0.6	-0.3	
25	13.6	-0.4	-0.4	-0.4	-0.2	
MAX	15.4	0.3	0.4	0.1	0.6	
MIN	13.2	-2.0	-1.9	-2.0	-2.1	
AVG	13.9	-0.6	-0.5	-0.6	0.0	
STD	0.6	0.5	0.5	0.5	0.6	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	

	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A				File #:	20914503
Description:	30 Au				Sample ID:	3
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.7	-0.4	-0.4	-0.4	0.2	
2	13.3	-0.3	-0.2	-0.3	1.0	
3	13.6	-0.4	-0.4	-0.5	0.7	
4	13.7	-0.5	-0.4	-0.5	0.5	
5	13.6	-0.6	-0.5	-0.6	1.0	
6	13.7	-0.6	-0.4	-0.6	0.0	
7	14.3	-0.6	-0.6	-0.7	1.1	
8	14.7	-1.1	-0.9	-1.3	-0.9	
9	14.2	-0.3	-0.3	-0.5	0.0	
10	14.9	-0.8	-0.7	-0.9	0.0	
11	14.8	-0.9	-0.8	-0.9	0.6	
12	15.3	-1.2	-1.1	-1.4	-0.8	
13	13.9	-0.2	0.1	-0.2	0.5	
14	15.2	-1.2	-0.9	-1.3	-0.8	
15	14.4	-0.6	-0.4	-0.6	0.0	
16	14.9	-1.2	-0.9	-1.2	-0.3	
17	14.2	-0.5	-0.3	-0.6	-0.3	
18	13.8	-0.2	0.0	-0.3	-0.1	
19	14.3	-0.4	-0.3	-0.4	-0.2	
20	13.8	-0.8	-0.5	-0.4	1.1	
21	13.3	-0.5	-0.3	-0.4	0.1	
22	13.9	-0.6	-0.4	-0.5	1.1	
23	13.7	-0.3	-0.2	-0.3	0.3	
24	13.7	-0.7	-0.5	-0.7	-0.5	
25	13.9	-0.7	-0.5	-0.6	-0.5	

					File #:	20914503
			Delta values			
			units: milliohms			
MAX	15.3	-0.2	0.1	-0.2	1.1	
MIN	13.3	-1.2	-1.1	-1.4	-0.9	
AVG	14.1	-0.6	-0.5	-0.6	0.1	
STD	0.6	0.3	0.3	0.3	0.6	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A				File #:	20914504
Description:	30 Au				Sample ID:	4
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.6	-0.3	-0.2	-0.4	0.4	
2	13.7	-0.4	-0.3	-0.4	0.4	
3	13.9	-0.4	-0.4	0.0	0.0	
4	13.6	-0.1	-0.1	0.0	0.5	
5	13.6	-0.2	-0.2	-0.3	0.1	
6	13.7	-0.3	-0.3	-0.5	0.0	
7	14.1	-0.6	-0.5	-0.6	-0.2	
8	14.4	-0.9	-0.8	-0.9	-0.1	
9	14.3	-0.6	-0.6	-0.6	0.2	
10	14.9	-1.4	-1.3	-1.3	-0.4	
11	14.8	-1.2	-1.1	-1.1	-0.5	
12	14.6	-1.0	-0.9	-0.9	-0.1	
13	14.8	-1.0	-1.0	-1.1	0.9	
14	14.7	-0.8	-0.8	-1.0	-0.1	
15	15.4	-1.5	-1.4	-1.5	-0.1	
16	14.9	-1.0	-1.1	-1.4	0.7	
17	14.3	-0.5	-0.5	-0.8	-0.2	
18	14.4	-0.6	-0.5	-0.7	-0.3	
19	14.6	-0.6	-0.5	-0.7	-0.3	
20	13.8	-0.7	-0.4	-0.5	-0.1	
21	13.9	-0.7	-0.4	-0.6	0.2	
22	14.0	-0.6	-0.4	-1.7	0.6	
23	13.8	-0.5	-0.3	-0.4	0.1	
24	13.7	-0.5	-0.3	-0.5	0.0	
25	14.1	-0.7	-0.5	-6.1	0.0	

					File #:	20914504
			Delta values			
			units: milliohms			
MAX	15.4	-0.1	-0.1	0.0	0.9	
MIN	13.6	-1.5	-1.4	-6.1	-0.5	
AVG	14.2	-0.7	-0.6	-1.0	0.1	
STD	0.5	0.4	0.4	1.2	0.3	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A				File #:	20914505
Description:	30 Au				Sample ID:	5
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.0	-0.1	0.0	-0.1	0.4	
2	13.2	-0.3	-0.2	-0.4	0.2	
3	13.4	-0.3	-0.3	-0.4	-0.1	
4	12.8	0.1	0.3	0.2	0.5	
5	13.0	0.0	0.0	-0.1	0.3	
6	13.0	0.0	0.1	-0.1	0.4	
7	14.0	-0.7	-1.0	-0.8	1.1	
8	14.3	-1.0	-0.9	-0.9	0.1	
9	14.5	-1.2	-1.3	-1.3	1.3	
10	14.8	-1.3	-1.2	-1.4	0.8	
11	14.9	-1.4	-0.7	-0.6	0.6	
12	14.7	-1.5	-1.4	-1.6	0.7	
13	14.5	-0.4	-0.8	-1.0	0.8	
14	15.0	-0.7	-1.0	-1.2	1.3	
15	14.0	-0.2	-0.4	-0.6	1.1	
16	13.4	0.3	0.2	0.0	0.5	
17	13.8	0.0	-0.2	-0.4	1.5	
18	14.8	-0.9	-0.9	-1.1	-0.1	
19	14.6	-0.4	-0.6	-0.8	0.8	
20	13.4	-0.4	-0.1	-0.5	0.5	
21	13.4	-0.2	-0.2	-0.3	0.4	
22	13.9	-0.2	-0.2	-0.3	0.0	
23	13.5	-0.1	0.4	-0.2	0.3	
24	13.5	-0.3	-0.3	-0.5	0.6	
25	13.9	-0.7	-0.6	-0.8	0.4	
MAX	15.0	0.3	0.4	0.2	1.5	
MIN	12.8	-1.5	-1.4	-1.6	-0.1	
AVG	13.9	-0.5	-0.5	-0.6	0.6	
STD	0.7	0.5	0.5	0.5	0.4	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A				File #:	20914506
Description:	30 Au				Sample ID:	6
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.3	-0.5	-0.3	-0.4	-0.1	
2	13.4	-0.5	-0.4	-0.5	-0.2	
3	14.9	-0.6	-0.4	-0.6	0.6	
4	13.1	-0.4	-0.1	-0.3	0.2	
5	13.0	-0.2	0.0	-0.4	0.2	
6	13.0	-0.3	0.0	0.4	0.2	
7	13.9	-0.3	-0.2	-0.4	0.6	
8	14.0	-0.4	-0.3	-0.2	0.1	
9	14.6	-0.9	-0.9	-1.5	0.1	
10	14.0	-0.7	-0.5	-0.4	0.1	
11	14.9	-1.6	-1.2	-1.8	-0.9	
12	14.4	-0.9	-0.5	0.7	-0.7	
13	14.8	-0.8	-0.8	-1.1	-0.6	
14	14.7	-0.7	-0.6	-1.3	0.4	
15	13.6	-0.1	0.0	-0.7	0.2	
16	14.7	-1.3	-1.0	-2.1	-0.8	
17	15.1	-1.2	-1.0	-1.4	-0.4	
18	13.5	0.0	0.1	-1.4	0.7	
19	14.4	-0.3	-0.3	-1.1	-0.4	
20	13.9	-1.0	-0.5	-1.1	-0.2	
21	13.8	-1.1	-0.8	-1.3	-0.6	
22	13.6	-0.8	-0.8	-0.9	-0.3	
23	13.4	-0.5	-0.3	-0.6	-0.1	
24	13.4	-0.5	-0.3	-0.6	-0.1	
25	13.5	-0.4	-0.2	-0.5	0.2	
MAX	15.1	0.0	0.1	0.7	0.7	
MIN	13.0	-1.6	-1.2	-2.1	-0.9	
AVG	14.0	-0.6	-0.5	-0.8	-0.1	
STD	0.6	0.4	0.4	0.6	0.4	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A				File #:	20914507
Description:	30 Au				Sample ID:	7
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.9	-0.5	-0.4	-0.5	1.1	
2	13.7	-0.3	-0.2	-0.4	0.5	
3	15.2	-1.0	-0.9	-1.3	0.8	
4	14.5	-0.3	-0.5	-1.0	0.6	
5	14.1	0.1	-0.1	-0.6	1.5	
6	13.7	0.2	0.1	-0.3	1.3	
7	14.8	-1.0	-0.9	-1.0	1.6	
8	15.3	-1.6	-1.3	-1.4	1.0	
9	13.8	-0.5	-0.3	-0.5	1.3	
10	14.6	-0.8	-0.7	-3.5	2.5	
11	14.0	-0.3	-0.3	-0.4	0.3	
12	15.2	-1.3	-1.0	-1.3	1.6	
13	14.7	-1.0	-0.8	-1.1	-0.6	
14	14.7	-0.5	-0.4	-0.7	1.1	
15	14.6	-1.1	-0.2	-1.3	-0.2	
16	14.1	-0.3	0.3	-0.5	1.1	
17	14.1	-0.3	-0.2	-0.4	0.2	
18	14.5	-0.5	-0.5	-0.7	1.3	
19	15.4	-1.6	-1.0	-1.5	-0.8	
20	14.0	-0.4	-0.3	-0.8	4.3	
21	14.0	-0.6	-0.6	-1.3	0.4	
22	14.4	-0.8	-0.6	-0.8	2.3	
23	14.1	-0.3	-0.2	-0.5	1.8	
24	14.0	-0.7	-0.6	-0.8	0.3	
25	14.0	-0.6	-0.4	-0.6	1.2	

					File #:	20914507
			Delta values			
			units: milliohms			
MAX	15.4	0.2	0.3	-0.3	4.3	
MIN	13.7	-1.6	-1.3	-3.5	-0.8	
AVG	14.4	-0.6	-0.5	-0.9	1.1	
STD	0.5	0.5	0.4	0.6	1.0	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A				File #:	20914508
Description:	30 Au				Sample ID:	8
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.8	-0.3	-0.2	-0.3	0.5	
2	13.9	-0.5	-0.4	-0.5	0.0	
3	13.9	-0.3	-0.1	-0.2	0.5	
4	14.2	-0.7	-0.4	-0.6	0.1	
5	14.1	-0.6	-0.4	-0.5	0.2	
6	14.0	-0.5	-0.2	-0.4	0.2	
7	14.7	-1.0	-1.1	-1.1	-0.2	
8	15.2	-1.6	-1.5	-1.6	-0.8	
9	15.6	-0.7	-0.6	-0.5	0.2	
10	15.5	-1.7	-1.7	-1.8	-1.4	
11	14.9	-1.2	-1.1	-1.3	-0.8	
12	13.9	-0.1	0.0	-0.2	1.1	
13	14.0	0.1	0.1	-0.1	0.4	
14	14.0	-0.3	-0.2	-0.4	1.9	
15	14.0	-0.3	-0.2	-0.3	0.3	
16	13.9	-0.3	-0.1	-0.3	1.8	
17	15.2	-1.2	-0.9	-1.1	-0.5	
18	15.0	-1.0	-0.9	-1.0	0.1	
19	14.5	-0.7	-0.6	-0.7	0.7	
20	14.4	-0.6	-0.4	-0.6	-0.1	
21	14.4	-0.8	-0.6	-0.8	0.3	
22	14.4	-0.6	-0.4	-0.6	0.0	
23	14.5	-0.9	-0.6	-0.9	0.9	
24	14.4	-0.5	-0.4	-0.6	0.1	
25	14.9	-0.9	-0.6	-1.0	-0.4	

					File #:	20914508
			Delta values			
			units: milliohms			
MAX	15.6	0.1	0.1	-0.1	1.9	
MIN	13.8	-1.7	-1.7	-1.8	-1.4	
AVG	14.5	-0.7	-0.5	-0.7	0.2	
STD	0.5	0.4	0.5	0.4	0.7	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

LLCR DATA FILES

FILE NUMBERS

MEC8-170-01-C-DV-A 50 Au

20914517
20914518
20914519
20914520
20914521
20914522
20914523
20914524

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914517
Description:	50 Au				Sample ID:	9
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	15.0	-0.8	-0.8	-0.9	-0.6	
2	15.0	-0.8	-0.7	-0.9	-0.4	
3	14.7	-0.6	-0.4	-0.6	-0.1	
4	14.7	-0.6	-0.6	-0.7	-0.2	
5	14.5	-0.3	-0.4	-0.5	0.0	
6	14.9	-0.6	-0.7	-0.7	-0.2	
7	14.8	0.0	-0.3	-0.4	0.0	
8	15.2	-0.5	-0.8	-0.8	-0.5	
9	14.9	0.0	-0.3	-0.5	-0.1	
10	14.8	-0.2	-0.3	-0.4	-0.1	
11	14.9	-0.3	-0.4	-0.5	-0.3	
12	14.7	0.0	-0.1	-0.3	0.2	
13	15.1	-0.3	-0.1	-0.3	0.3	
14	15.1	-0.1	-0.1	-0.3	0.5	
15	15.1	-0.2	-0.2	-0.4	-0.1	
16	14.8	0.0	0.0	-0.1	0.3	
17	15.0	0.0	0.0	-0.1	0.3	
18	15.0	-0.2	-0.2	-0.3	0.3	
19	15.2	0.2	0.0	-0.2	0.2	
20	14.7	-0.3	-0.3	-0.4	0.8	
21	15.4	-1.0	-0.8	-1.1	-0.1	
22	15.0	-0.7	-0.5	-0.7	-0.3	
23	14.5	-0.3	-0.1	-0.3	0.4	
24	14.8	-0.3	-0.1	-0.3	0.3	
25	15.1	-0.4	-0.3	-0.4	0.5	

					File #:	20914517
			Delta values			
			units: milliohms			
MAX	15.4	0.2	0.0	-0.1	0.8	
MIN	14.5	-1.0	-0.8	-1.1	-0.6	
AVG	14.9	-0.3	-0.3	-0.5	0.0	
STD	0.2	0.3	0.3	0.2	0.3	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914518
Description:	50 Au				Sample ID:	10
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	13.4	-0.2	-0.1	-0.3	0.5	
2	13.7	-0.2	-0.2	-0.4	0.6	
3	13.8	-0.6	-0.6	-0.7	0.6	
4	13.9	-0.6	-0.4	-0.6	0.1	
5	13.9	-0.3	-0.2	-0.3	0.4	
6	14.0	-0.6	-0.5	-0.6	0.0	
7	14.3	-0.6	-0.7	-0.7	-0.1	
8	14.0	-0.3	-0.3	-0.4	0.7	
9	14.6	-0.7	-0.7	-0.8	-0.2	
10	14.5	-0.7	-0.8	-0.9	0.7	
11	14.7	-1.2	-1.2	-1.4	-0.7	
12	13.9	-0.3	-0.2	-0.4	0.4	
13	14.3	-0.6	-0.4	-0.6	0.1	
14	14.1	-0.6	-0.2	-0.7	0.4	
15	14.4	-0.8	-0.6	-0.7	-0.3	
16	15.1	-1.3	-1.3	-1.4	-1.1	
17	14.4	-1.0	-0.8	-0.9	-0.3	
18	15.2	-1.4	-1.3	-1.1	-1.0	
19	14.7	-1.1	-1.0	-1.1	0.1	
20	14.0	-0.6	-0.4	-0.7	0.2	
21	14.4	-0.9	-0.7	-1.0	0.1	
22	14.4	-0.7	-0.6	-0.8	1.6	
23	13.9	-0.7	-0.6	-0.7	0.4	
24	14.0	-0.6	-0.4	-0.5	0.1	
25	14.3	-0.8	-0.5	-0.4	0.5	
MAX	15.2	-0.2	-0.1	-0.3	1.6	
MIN	13.4	-1.4	-1.3	-1.4	-1.1	
AVG	14.2	-0.7	-0.6	-0.7	0.1	
STD	0.4	0.3	0.3	0.3	0.6	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914519
Description:	50 Au				Sample ID:	11
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.1	-0.4	-0.2	-0.4	0.1	
2	14.3	-0.4	-0.3	-0.4	0.0	
3	14.2	-0.3	-0.2	-0.3	0.1	
4	14.2	-0.3	-0.2	-0.4	0.1	
5	14.0	-0.2	-0.2	-0.3	0.0	
6	14.0	-0.3	-0.2	-0.3	0.4	
7	14.6	-0.3	-0.2	-0.3	0.9	
8	14.5	-0.3	-0.2	-0.3	0.2	
9	14.7	-0.5	-0.3	-0.5	0.0	
10	14.6	-0.4	-0.2	-0.3	0.0	
11	14.6	-0.4	-0.3	-0.4	0.6	
12	14.7	-0.4	-0.5	-0.7	0.1	
13	14.5	-0.1	0.1	-1.1	0.2	
14	14.6	-0.2	0.2	-0.1	0.2	
15	14.5	-0.1	0.0	-0.1	0.2	
16	14.6	-0.2	0.1	0.6	2.8	
17	14.4	-0.2	0.1	0.0	1.5	
18	14.4	-0.2	0.0	-0.2	0.6	
19	14.6	-0.1	0.1	-0.1	0.4	
20	14.1	-0.4	-0.2	-0.3	0.2	
21	14.2	-0.5	-0.4	-0.4	-0.1	
22	14.3	-0.4	-0.2	-0.3	0.6	
23	14.1	-0.4	-0.3	-0.4	0.0	
24	14.4	-0.5	-0.3	-0.5	-0.1	
25	14.4	-0.4	-0.2	-0.4	0.0	

					File #:	20914519
			Delta values			
			units: milliohms			
MAX	14.7	-0.1	0.2	0.6	2.8	
MIN	14.0	-0.5	-0.5	-1.1	-0.1	
AVG	14.4	-0.3	-0.2	-0.3	0.4	
STD	0.2	0.1	0.2	0.3	0.6	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914520
Description:	50 Au				Sample ID:	12
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.5	-0.7	-0.6	-0.7	0.0	
2	14.9	-1.0	-0.8	-1.0	-0.2	
3	14.9	-1.2	-1.0	-1.1	0.6	
4	14.8	-0.9	-0.7	-0.9	0.6	
5	14.8	-1.0	-0.8	-1.0	0.7	
6	15.0	-1.2	-1.0	-1.2	0.1	
7	14.6	0.4	-0.1	-0.3	0.4	
8	14.9	-0.4	-0.6	-0.7	-0.5	
9	15.2	-0.9	-0.9	-1.1	-0.4	
10	14.8	-0.3	-0.4	-0.6	0.0	
11	14.6	-0.3	-0.3	-0.4	0.2	
12	14.8	-0.7	-0.7	-0.8	-0.3	
13	14.8	-0.7	-0.6	-0.8	-0.4	
14	14.8	-0.7	-0.6	-0.8	-0.5	
15	14.2	0.0	0.1	-0.1	0.2	
16	14.7	-0.4	-0.3	-0.5	-0.3	
17	14.8	-0.5	-0.4	-0.5	-0.2	
18	14.9	-0.6	-0.4	-1.5	-0.4	
19	14.8	-0.5	-0.4	-0.5	-0.6	
20	14.7	-0.7	-0.5	-0.6	0.0	
21	14.2	-0.4	0.0	-0.3	0.1	
22	14.6	-0.6	-0.5	-0.8	-0.4	
23	14.6	-0.7	-0.6	-0.8	-0.3	
24	14.5	-0.6	-0.4	-0.8	-0.7	
25	14.7	-0.8	-0.6	-0.9	-0.4	

					File #:	20914520
			Delta values			
			units: milliohms			
MAX	15.2	0.4	0.1	-0.1	0.7	
MIN	14.2	-1.2	-1.0	-1.5	-0.7	
AVG	14.7	-0.6	-0.5	-0.7	-0.1	
STD	0.2	0.3	0.3	0.3	0.4	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914521
Description:	50 Au				Sample ID:	13
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.0	-0.2	0.0	-0.1	0.3	
2	14.5	-0.5	-0.5	-0.5	-0.5	
3	14.8	-0.9	-1.0	-1.0	-1.1	
4	14.4	-0.6	-0.6	-0.7	-0.6	
5	14.4	-0.5	-0.5	-0.7	-0.3	
6	14.3	-0.6	-0.6	-0.7	-0.5	
7	14.4	-0.1	-0.2	-0.2	0.0	
8	14.2	0.3	0.1	0.0	0.2	
9	14.5	0.0	-0.2	-0.3	0.3	
10	14.5	-0.1	-0.1	-0.2	0.0	
11	14.6	-0.4	-0.2	-0.4	0.4	
12	14.7	-0.4	-0.4	-0.5	-0.1	
13	14.6	-0.4	-0.3	-0.5	1.2	
14	14.6	-0.4	-0.3	-0.5	0.1	
15	14.6	-0.3	-0.2	-0.5	0.5	
16	14.9	-0.5	-0.5	-0.8	-0.4	
17	14.2	-0.2	-0.1	-0.3	0.0	
18	14.4	-0.3	-0.3	-0.5	-0.2	
19	14.8	-0.4	-0.2	-0.5	-0.3	
20	14.1	-0.2	-0.4	-0.5	0.5	
21	14.2	-0.4	-0.4	-0.6	0.1	
22	14.2	-0.2	-0.1	-0.3	0.2	
23	13.9	-0.3	-0.2	-0.3	0.1	
24	14.1	-0.2	-0.2	-0.3	0.1	
25	14.5	-0.5	-0.3	-0.5	0.6	
MAX	14.9	0.3	0.1	0.0	1.2	
MIN	13.9	-0.9	-1.0	-1.0	-1.1	
AVG	14.4	-0.3	-0.3	-0.5	0.0	
STD	0.3	0.2	0.2	0.2	0.5	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	AJP	AJP	
Equip ID	1047	323	1047	244	244	
	476	297	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914522
Description:	50 Au				Sample ID:	14
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.0	-0.6	-0.5	-0.5	-0.2	
2	13.7	-0.3	-0.2	0.0	0.2	
3	13.9	-0.4	-0.5	-0.3	-0.1	
4	14.2	-0.9	-0.8	-0.6	-0.4	
5	13.8	-0.5	-0.4	0.0	-0.1	
6	13.9	-0.7	-0.5	-0.4	-0.1	
7	14.1	0.0	-0.1	-0.1	0.3	
8	14.2	-0.2	-0.3	-0.2	0.5	
9	14.2	-0.3	-0.2	-0.3	0.5	
10	14.2	-0.3	-0.1	-0.1	0.1	
11	14.4	-0.6	-0.5	-0.6	0.3	
12	14.7	-0.8	-0.7	-0.6	-0.7	
13	14.0	-0.4	-0.4	0.1	-0.2	
14	14.5	-0.8	-0.8	-0.2	1.4	
15	14.1	-0.7	-0.6	-0.2	-0.2	
16	14.2	-0.7	-0.6	-0.3	-0.2	
17	14.1	-0.6	-0.3	-0.3	-0.2	
18	14.0	-0.5	-0.3	-0.1	0.0	
19	14.2	-0.6	-0.3	0.0	-0.2	
20	13.6	-0.5	-0.2	0.0	-0.3	
21	13.6	-0.3	-0.3	-0.3	-0.3	
22	13.3	-0.2	-0.1	-0.1	0.0	
23	13.6	-0.2	-0.1	-0.3	-0.2	
24	13.8	-0.1	-0.2	-0.3	0.1	
25	13.9	-1.0	-1.0	-0.7	2.2	
MAX	14.7	0.0	-0.1	0.1	2.2	
MIN	13.3	-1.0	-1.0	-0.7	-0.7	
AVG	14.0	-0.5	-0.4	-0.2	0.1	
STD	0.3	0.3	0.2	0.2	0.6	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	S.Rath	S.Rath	
Equip ID	1047	323	1047	1546	1546	
	476	297	476	1032	1032	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914523
Description:	50 Au				Sample ID:	15
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14 MFG	1X	
1	14.3	-0.6	-0.5	-0.5	0.3	
2	14.2	-0.4	-0.4	-0.4	0.5	
3	14.3	-0.3	-0.3	-0.2	1.2	
4	13.9	-0.1	0.0	0.2	1.7	
5	14.0	-0.2	-0.1	-0.1	0.6	
6	13.9	-0.1	-0.1	0.1	0.5	
7	14.3	-0.2	-0.3	-0.2	0.3	
8	14.1	0.0	0.1	0.0	0.4	
9	14.6	-0.5	-0.5	-0.6	0.1	
10	14.1	-0.1	0.1	-0.1	0.6	
11	14.1	-0.1	0.0	0.0	0.6	
12	14.3	-0.2	-0.1	0.0	0.4	
13	14.2	0.0	0.2	0.1	1.1	
14	14.1	-0.1	0.2	0.1	0.6	
15	14.1	-0.2	-0.1	-0.2	0.5	
16	14.0	-0.2	0.0	0.1	0.4	
17	14.3	-0.2	-0.1	0.1	0.5	
18	14.2	0.1	0.2	0.3	0.5	
19	14.5	-0.1	0.1	-0.9	0.8	
20	14.5	-0.7	-0.8	-0.6	0.1	
21	14.4	-0.5	-0.4	-0.5	2.1	
22	14.5	-0.5	-0.5	-0.6	0.0	
23	14.2	-0.4	-0.3	-0.3	0.4	
24	14.4	-0.5	-0.3	-0.3	0.7	
25	14.5	-0.4	-0.3	-0.4	0.3	

					File #:	20914523
			Delta values			
			units: milliohms			
MAX	14.6	0.1	0.2	0.3	2.1	
MIN	13.9	-0.7	-0.8	-0.9	0.0	
AVG	14.2	-0.3	-0.2	-0.2	0.6	
STD	0.2	0.2	0.3	0.3	0.5	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	S.Rath	S.Rath	
Equip ID	1047	323	1047	1032	1032	
	476	297	476	1546	1546	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914524
Description:	50 Au				Sample ID:	16
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.1	-0.4	-0.1	0.6	0.4	
2	14.4	-0.6	-0.3	-1.1	0.6	
3	14.0	-0.5	-0.1	-0.2	2.5	
4	14.4	-0.6	-0.4	-0.4	1.4	
5	14.4	-0.5	-0.3	-0.3	0.6	
6	14.6	-0.7	-0.5	-0.6	0.5	
7	14.2	0.1	0.3	0.1	0.3	
8	14.0	-0.2	-0.1	-0.1	0.6	
9	14.1	-0.1	0.1	0.1	0.4	
10	14.2	-0.1	0.2	0.3	0.6	
11	14.4	-0.3	-0.1	0.1	0.2	
12	14.2	-0.3	0.1	0.1	0.6	
13	14.9	-0.6	-0.4	-0.4	1.0	
14	14.6	-0.3	-0.2	0.0	1.0	
15	14.9	-0.4	-0.1	-0.2	1.0	
16	14.6	-0.1	0.1	0.1	0.7	
17	14.3	-0.3	-0.1	0.0	1.1	
18	14.5	-0.2	-0.1	-0.2	0.6	
19	14.8	0.1	-0.3	-0.4	0.8	
20	14.6	-0.8	-0.6	-0.5	0.5	
21	14.8	-1.0	-0.6	-0.6	2.1	
22	15.1	-1.2	-0.9	-0.8	0.9	
23	14.5	-0.5	-0.3	-0.3	0.2	
24	14.8	-0.7	-0.4	-0.5	0.3	
25	14.9	-0.6	0.0	-0.2	0.7	

					File #:	20914524
			Delta values			
			units: milliohms			
MAX	15.1	0.1	0.3	0.6	2.5	
MIN	14.0	-1.2	-0.9	-1.1	0.2	
AVG	14.5	-0.4	-0.2	-0.2	0.8	
STD	0.3	0.3	0.3	0.4	0.5	
Open	0	0	0	0	0	
Tech	LL	DAM	LL	S.Rath	S.Rath	
Equip ID	1047	323	1047	1546	1546	
	476	297	476	1032	1032	

LLCR DATA FILES

FILE NUMBERS

MEC8-120-01-C-DV-A 30 Au

20914509
20914510
20914511
20914512
20914513
20914514
20914515
20914516

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914509
Description:	30 Au				Sample ID:	17
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.8	0.3	0.3	0.2	0.4	
2	14.9	0.0	-0.1	-0.2	0.1	
3	14.8	-0.1	-0.3	-0.6	0.2	
4	14.1	0.2	0.4	0.1	0.7	
5	15.0	0.2	0.0	-0.3	0.6	
6	15.0	0.5	-0.1	-0.1	0.5	
7	14.9	-0.1	0.0	-0.1	0.4	
8	15.1	-0.6	-0.4	-0.7	-0.2	
9	17.6	-3.1	-2.9	-2.8	-2.9	
10	15.0	-0.3	0.0	0.0	0.4	
11	14.8	-0.1	0.2	0.2	2.0	
12	14.9	-0.1	0.0	-0.2	0.6	
13	14.8	0.0	0.2	0.0	0.3	
14	15.3	-0.3	-0.2	-0.4	-0.1	
15	14.8	-0.3	0.0	-0.2	0.1	
16	14.6	-0.1	0.1	0.0	0.4	
17	14.6	-0.1	0.0	-0.1	0.0	
18	14.7	-0.2	0.0	0.0	0.0	
19	14.9	-0.4	-0.1	0.0	0.1	
20	14.8	0.8	0.4	0.5	2.1	
21	15.1	0.5	0.1	0.3	0.4	
22	15.0	0.1	0.0	0.0	0.3	
23	14.9	0.2	0.0	-0.2	0.2	
24	14.6	0.6	0.3	0.2	0.3	
25	15.1	0.0	0.0	0.0	-0.2	

					File #:	20914509
			Delta values			
			units: milliohms			
MAX	17.6	0.8	0.4	0.5	2.1	
MIN	14.1	-3.1	-2.9	-2.8	-2.9	
AVG	15.0	-0.1	-0.1	-0.2	0.3	
STD	0.6	0.7	0.6	0.6	0.8	
Open	0	0	0	0	0	
Tech	LL	BE	LL	AJP	AJP	
Equip ID	1047	601	1047	244	244	
	476	677	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914510
Description:	30 Au				Sample ID:	18
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.3	-0.6	-0.5	-0.6	-0.5	
2	14.4	-0.6	-0.3	-0.6	-0.6	
3	14.1	-0.2	-0.4	-0.5	-0.5	
4	14.2	-0.2	-0.3	-0.4	-0.5	
5	14.0	-0.1	-0.2	-0.3	-0.5	
6	14.0	0.1	-0.3	-0.5	-0.2	
7	14.3	-0.6	-0.4	-0.5	-0.2	
8	14.3	-0.3	-0.3	-0.3	-0.1	
9	14.2	-0.2	-0.3	-0.3	-0.1	
10	14.4	-0.2	-0.2	-0.2	0.0	
11	14.2	-0.2	-0.1	-0.2	-0.1	
12	14.3	-0.1	-0.4	-0.4	-0.3	
13	14.4	-0.7	-0.2	-0.2	-0.2	
14	14.3	-0.2	-0.1	0.0	0.0	
15	14.2	-0.1	0.0	0.0	0.2	
16	14.2	-0.2	0.0	0.1	0.2	
17	14.1	-0.2	0.0	-0.1	0.2	
18	14.3	-0.4	-0.1	-0.1	-0.1	
19	14.2	0.6	-0.1	-0.1	0.0	
20	13.9	0.0	0.0	0.0	0.0	
21	13.9	0.1	-0.1	-0.1	0.0	
22	14.0	-0.3	-0.2	-0.2	0.0	
23	13.9	-0.3	-0.1	-0.2	0.0	
24	13.9	-0.4	-0.2	-0.1	0.1	
25	14.2	-0.5	-0.2	-0.2	-0.2	
MAX	14.4	0.6	0.0	0.1	0.2	
MIN	13.9	-0.7	-0.5	-0.6	-0.6	
AVG	14.2	-0.2	-0.2	-0.2	-0.1	
STD	0.2	0.3	0.1	0.2	0.2	
Open	0	0	0	0	0	
Tech	LL	BE	LL	AJP	AJP	
Equip ID	1047	601	1047	244	244	
	476	677	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914511
Description:	30 Au				Sample ID:	19
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.7	-0.6	-0.5	-0.5	-0.3	
2	14.6	-0.8	-0.7	-0.7	0.0	
3	14.6	-0.7	-0.5	-0.5	0.1	
4	14.5	-0.5	-0.3	-0.4	-0.1	
5	15.0	-0.7	-0.5	-0.5	-0.6	
6	14.8	-0.6	-0.5	-0.4	-0.4	
7	14.8	-0.3	-0.2	-0.4	-0.2	
8	14.7	-0.6	-0.4	-0.2	-0.3	
9	14.6	-0.3	-0.2	0.0	0.1	
10	14.8	-0.5	-0.2	0.0	-0.1	
11	14.7	-0.3	-0.3	0.5	0.2	
12	15.1	-0.7	-0.5	0.0	0.0	
13	15.0	-0.5	-0.4	-0.1	-0.1	
14	15.0	-0.6	-0.5	-0.1	-0.3	
15	14.9	-0.6	-0.6	-0.4	-0.4	
16	14.8	-0.5	-0.5	-0.3	-0.3	
17	14.5	-0.2	-0.2	0.0	0.2	
18	14.8	-0.5	-0.5	0.8	-0.5	
19	14.7	-0.1	-0.4	0.4	0.4	
20	14.9	-0.5	-0.5	0.1	-0.4	
21	14.8	-0.4	-0.7	0.1	-0.3	
22	14.6	-0.4	-0.5	-0.3	0.0	
23	14.7	-0.5	-0.6	-0.2	-0.5	
24	14.7	-0.5	-0.6	-0.2	0.1	
25	14.9	-0.5	-0.6	-0.2	-0.5	

					File #:	20914511
			Delta values			
			units: milliohms			
MAX	15.1	-0.1	-0.2	0.8	0.4	
MIN	14.5	-0.8	-0.7	-0.7	-0.6	
AVG	14.8	-0.5	-0.4	-0.1	-0.2	
STD	0.1	0.2	0.2	0.3	0.3	
Open	0	0	0	0	0	
Tech	LL	BE	LL	AJP	AJP	
Equip ID	1047	601	1047	244	244	
	476	677	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914512
Description:	30 Au				Sample ID:	20
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-life	7D MFG	14D MFG	1X	
1	14.2	0.0	-0.3	-0.4	-0.2	
2	14.1	-0.4	-0.4	-0.5	0.1	
3	14.1	-0.2	-0.2	-0.4	0.3	
4	14.1	-0.4	-0.5	-0.6	0.2	
5	14.0	-0.2	-0.3	-0.4	0.2	
6	14.0	-0.4	-0.4	-0.5	0.5	
7	13.9	-0.3	-0.5	-0.3	-0.2	
8	14.1	-0.4	-0.3	-0.3	0.3	
9	14.2	-0.3	-0.2	-0.3	0.2	
10	14.3	-0.2	-0.1	-0.2	0.3	
11	14.3	-0.2	-0.1	-0.2	1.2	
12	14.3	-0.1	-0.2	-0.2	0.2	
13	14.6	-0.4	-0.3	-0.3	0.6	
14	14.4	-0.3	-0.2	-0.1	0.4	
15	14.3	-0.3	-0.5	-0.1	0.2	
16	14.1	0.0	0.2	0.3	0.9	
17	14.1	0.2	0.0	0.0	3.8	
18	13.9	0.2	-0.1	-0.1	0.3	
19	14.7	-0.2	-0.4	-0.3	2.0	
20	14.2	-0.4	-0.3	-0.5	0.5	
21	14.2	-0.1	0.0	-0.3	1.0	
22	14.4	-0.4	-0.4	-0.6	0.0	
23	14.0	-0.2	-0.2	-0.4	0.3	
24	13.8	-0.1	0.0	-0.2	0.5	
25	14.1	0.0	-0.1	-0.3	0.9	

					File #:	20914512
			Delta values			
			units: milliohms			
MAX	14.7	0.2	0.2	0.3	3.8	
MIN	13.8	-0.4	-0.5	-0.6	-0.2	
AVG	14.2	-0.2	-0.2	-0.3	0.6	
STD	0.2	0.2	0.2	0.2	0.8	
Open	0	0	0	0	0	
Tech	LL	BE	LL	AJP	AJP	
Equip ID	1047	601	1047	244	244	
	476	677	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914513
Description:	30 Au				Sample ID:	21
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.2	-0.5	-0.6	-0.5	-0.3	
2	14.3	-0.8	-0.7	-0.8	-0.5	
3	13.9	-0.5	-0.4	-0.4	-0.3	
4	14.1	-0.7	-0.6	-0.6	-0.4	
5	14.1	-0.7	-0.6	-0.7	-0.4	
6	14.4	-1.0	-0.9	-0.8	-0.3	
7	14.3	-0.5	-1.0	-0.5	-0.2	
8	14.1	-0.5	-0.3	-0.4	-0.2	
9	13.9	-0.3	-0.1	-0.1	0.1	
10	14.1	-0.4	-0.1	-0.1	0.2	
11	14.2	-0.4	-0.2	-0.2	0.0	
12	14.1	-0.4	0.1	0.1	0.4	
13	14.3	-0.3	0.1	0.1	0.6	
14	14.3	-0.5	-0.2	-0.2	0.3	
15	14.1	-0.3	0.1	0.2	0.5	
16	14.2	-0.4	-0.2	-0.1	0.3	
17	14.1	-0.5	-0.2	-0.2	0.4	
18	13.9	-0.3	-0.2	-0.1	0.3	
19	14.0	-0.3	0.0	0.0	0.5	
20	14.1	-0.6	-0.4	-0.5	-0.1	
21	14.1	-0.5	-0.5	-0.5	0.2	
22	13.9	-0.2	-0.3	-0.3	0.1	
23	13.9	-0.1	-0.2	-0.3	0.1	
24	13.7	-0.2	-0.1	-0.1	0.1	
25	14.0	-0.4	-0.4	-0.4	0.1	
MAX	14.4	-0.1	0.1	0.2	0.6	
MIN	13.7	-1.0	-1.0	-0.8	-0.5	
AVG	14.1	-0.5	-0.3	-0.3	0.1	
STD	0.2	0.2	0.3	0.3	0.3	
Open	0	0	0	0	0	
Tech	LL	BE	LL	S.Rath	S.Rath	
Equip ID	1047	601	1047	1032	1032	
	476	677	476	1546	1546	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914514
Description:	30 Au				Sample ID:	22
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.4	-0.4	-0.4	-0.4	0.0	
2	14.8	-0.6	-0.6	-0.5	-0.5	
3	14.8	-0.4	-0.6	-0.5	-0.6	
4	14.9	-0.8	-0.9	-0.7	-0.5	
5	14.9	-0.7	-0.6	-0.5	-0.3	
6	14.7	-0.4	-0.4	-0.3	-0.4	
7	15.0	-0.6	-0.6	-0.5	-0.2	
8	15.2	-0.9	-0.9	-1.0	-1.8	
9	14.8	-0.7	-0.7	-0.7	-0.4	
10	15.3	-0.7	-0.8	-0.8	-0.5	
11	15.1	-0.5	-0.6	-0.6	0.1	
12	14.9	-0.4	-0.5	-0.6	-0.3	
13	15.1	-0.6	-0.6	-0.6	-1.1	
14	14.9	-0.7	-0.6	-0.6	-1.1	
15	14.8	-0.7	-0.5	-0.6	0.0	
16	17.5	-3.5	-3.2	-3.2	-2.7	
17	14.7	-0.5	-0.3	-0.3	0.0	
18	14.6	-0.7	-0.5	-0.3	0.2	
19	14.9	-0.5	-0.4	-0.3	1.0	
20	14.8	-0.5	-0.6	-0.7	-0.1	
21	14.8	-0.8	-0.8	-0.8	-0.5	
22	14.1	0.1	0.1	-0.1	0.0	
23	14.6	-0.4	-0.3	-0.4	-0.1	
24	14.5	-0.6	-0.5	-0.6	-0.4	
25	14.8	-0.7	-0.7	-0.8	-0.4	
MAX	17.5	0.1	0.1	-0.1	1.0	
MIN	14.1	-3.5	-3.2	-3.2	-2.7	
AVG	14.9	-0.7	-0.7	-0.6	-0.4	
STD	0.6	0.6	0.6	0.6	0.7	
Open	0	0	0	0	0	
Tech	LL	BE	LL	S.Rath	S.Rath	
Equip ID	1047	601	1047	1032	1032	
	476	677	476	1546	1546	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914515
Description:	30 Au				Sample ID:	23
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.6	-0.2	-0.5	-0.6	-0.2	
2	14.9	-0.6	-0.9	-0.8	-0.7	
3	15.1	-1.0	-1.1	-1.1	-1.0	
4	14.3	-0.2	-0.4	-0.4	-0.4	
5	14.1	0.0	-0.1	-0.2	-0.1	
6	14.4	-0.5	-0.5	-0.5	-0.2	
7	14.7	0.0	-0.1	-0.1	0.3	
8	14.7	-0.1	-0.2	-0.2	0.3	
9	14.5	-0.1	-0.1	0.0	0.3	
10	14.6	-0.1	-0.2	-0.2	0.2	
11	14.7	-0.2	-0.3	0.0	0.2	
12	14.5	-0.2	-0.3	-0.2	-0.2	
13	14.7	-0.1	-0.2	-0.2	0.3	
14	14.5	0.1	0.0	0.0	0.1	
15	14.7	-0.1	-0.1	-0.1	0.1	
16	14.8	-0.3	-0.3	-0.3	0.1	
17	14.9	-0.3	-0.4	-0.3	0.1	
18	14.6	-0.4	-0.4	-0.4	0.0	
19	14.6	-0.1	0.0	0.0	0.5	
20	14.4	-0.1	0.1	-0.1	-0.1	
21	14.4	0.0	0.1	-0.2	-0.1	
22	14.3	0.1	0.1	-0.1	0.0	
23	14.5	0.1	0.1	-0.1	-0.1	
24	14.5	-0.3	-0.2	-0.4	-0.2	
25	14.6	-0.5	-0.3	-0.6	-0.2	
MAX	15.1	0.1	0.1	0.0	0.5	
MIN	14.1	-1.0	-1.1	-1.1	-1.0	
AVG	14.6	-0.2	-0.2	-0.3	0.0	
STD	0.2	0.3	0.3	0.3	0.3	
Open	0	0	0	0	0	
Tech	LL	BE	LL	AJP	AJP	
Equip ID	1047	601	1047	244	244	
	476	677	476	1116	1116	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A				File #:	20914516
Description:	30 Au				Sample ID:	24
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	27	31	26	34	34	
Date:	16Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.0	-0.2	-0.3	-0.2	0.1	
2	13.8	0.0	0.0	0.0	0.1	
3	14.0	-0.2	-0.1	-0.3	-0.2	
4	13.8	0.0	0.2	0.0	0.6	
5	13.9	-0.3	0.0	-0.2	0.3	
6	13.8	-0.3	-0.2	-0.4	0.0	
7	14.1	-0.1	0.1	-0.1	-0.2	
8	14.1	-0.1	0.2	-0.1	0.1	
9	13.9	-0.2	0.1	-0.1	0.3	
10	14.2	-0.1	0.1	0.0	0.6	
11	14.2	-0.3	0.3	0.1	0.2	
12	14.2	-0.3	-0.1	-0.3	-0.3	
13	14.1	-0.1	0.1	-0.1	0.1	
14	14.0	-0.2	0.1	-0.1	0.0	
15	14.1	0.0	0.2	0.0	0.2	
16	14.1	0.0	0.2	0.0	0.5	
17	14.2	-0.2	0.2	0.0	0.0	
18	14.0	-0.1	0.2	-0.1	0.2	
19	14.3	-0.1	0.2	0.0	0.0	
20	14.1	-0.2	0.0	-0.2	0.1	
21	13.8	-0.1	0.1	-0.2	0.3	
22	14.0	0.0	0.1	-0.1	0.1	
23	13.9	-0.3	-0.1	-0.3	0.0	
24	14.0	-0.2	0.2	-0.2	-0.4	
25	14.1	0.1	0.6	0.2	0.4	
MAX	14.3	0.1	0.6	0.2	0.6	
MIN	13.8	-0.3	-0.3	-0.4	-0.4	
AVG	14.0	-0.1	0.1	-0.1	0.1	
STD	0.1	0.1	0.2	0.1	0.2	
Open	0	0	0	0	0	
Tech	LL	BE	LL	AJP	AJP	
Equip ID	1047	601	1047	244	244	
	476	677	476	1116	1116	

LLCR DATA FILES

FILE NUMBERS

MEC8-120-01-C-DV-A 50 Au

20914525
20914526
20914527
20914528
20914529
20914530
20914531
20914532

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A 50Au				File #:	20914525
Description:	50 Au				Sample ID:	25
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14 MFG	1X	
1	13.8	-0.1	0.0	0.0	0.6	
2	13.7	-0.3	-0.3	-0.3	0.5	
3	13.6	-0.1	-0.3	-0.2	0.7	
4	13.4	0.1	-0.1	0.0	0.7	
5	13.5	0.0	-0.2	-0.2	0.7	
6	13.4	-0.1	-0.3	-0.2	0.6	
7	13.9	-0.7	-0.4	-0.6	0.2	
8	13.7	-0.5	-0.5	0.4	0.2	
9	13.7	-0.5	-0.5	-0.6	0.3	
10	14.1	-0.4	-0.5	3.3	0.7	
11	14.0	-0.3	-0.3	1.6	0.5	
12	13.7	-0.1	-0.2	-0.3	0.7	
13	14.3	-0.2	-0.3	-0.7	1.3	
14	13.7	-0.3	-0.2	-0.3	0.8	
15	13.9	-0.4	-0.4	-0.5	0.2	
16	13.9	-0.7	-0.7	-0.6	-0.2	
17	13.8	-0.6	-0.6	-0.3	0.0	
18	14.0	-0.5	-0.6	-0.5	-0.2	
19	13.9	-0.5	-0.4	-0.4	0.0	
20	13.5	-0.1	-0.2	-0.2	0.6	
21	13.6	-0.2	-0.3	-0.4	0.1	
22	13.4	-0.1	-0.1	-0.1	0.7	
23	13.7	-0.1	-0.2	-0.4	0.2	
24	13.6	-0.3	-0.1	-0.4	0.9	
25	13.6	-0.2	-0.1	-0.2	0.0	

					File #:	20914525
			Delta values			
			units: milliohms			
MAX	14.3	0.1	0.0	3.3	1.3	
MIN	13.4	-0.7	-0.7	-0.7	-0.2	
AVG	13.7	-0.3	-0.3	-0.1	0.4	
STD	0.2	0.2	0.2	0.8	0.4	
Open	0	0	0	0	0	
Tech	LL	BE	LL	S.Rath	S.Rath	
Equip ID	1047	601	1047	1032	1032	
	476	677	476	1546	1546	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A 50Au				File #:	20914526
Description:	50 Au				Sample ID:	26
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T-Life	7D MFG	14D MFG	1X	
1	14.4	-1.2	-1.2	-0.9	-0.8	
2	13.4	-0.6	-0.6	-0.3	-0.1	
3	13.4	-0.6	-0.5	0.0	0.2	
4	13.5	-0.6	-0.6	-0.2	0.2	
5	13.4	-0.4	-0.4	0.1	0.5	
6	13.3	-0.3	-0.4	0.1	0.1	
7	15.0	-1.7	-1.6	-1.6	-0.9	
8	14.4	-1.2	-1.1	-1.0	-0.4	
9	14.7	-1.4	-1.2	-1.3	-0.7	
10	14.5	-1.2	-1.2	-1.1	1.1	
11	14.6	-1.5	-1.4	-1.1	-0.4	
12	14.6	-0.9	-1.1	-1.3	-0.1	
13	15.0	-1.5	-1.6	-1.5	0.4	
14	14.1	-1.0	-0.8	-0.5	-0.2	
15	14.4	-1.0	-1.0	-1.0	-0.1	
16	14.0	-0.5	-0.4	-0.5	0.8	
17	14.8	-1.7	-1.6	-1.0	-0.7	
18	14.9	-1.6	-1.5	-1.6	-0.6	
19	14.7	-0.8	-0.7	-1.2	0.8	
20	13.9	-0.7	-0.8	0.5	0.0	
21	13.6	-0.2	-0.3	-0.1	2.4	
22	13.5	-0.4	-0.3	0.2	0.3	
23	13.3	0.0	-0.1	0.1	1.1	
24	13.4	-0.1	-0.2	0.1	0.6	
25	13.5	-0.3	-0.1	-0.3	0.7	
MAX	15.0	0.0	-0.1	0.5	2.4	
MIN	13.3	-1.7	-1.6	-1.6	-0.9	
AVG	14.1	-0.9	-0.8	-0.6	0.2	
STD	0.6	0.5	0.5	0.6	0.7	
Open	0	0	0	0	0	
Tech	LL	BE	LL	S.Rath	S.Rath	
Equip ID	1047	601	1047	1546	1546	
	476	677	476	1032	1032	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A 50Au				File #:	20914527
Description:	50 Au				Sample ID:	27
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	14.0	-0.1	-0.2	0.4	-0.3	
2	15.6	-1.5	-1.5	-1.2	0.3	
3	13.6	0.2	-0.1	0.1	0.2	
4	13.7	-0.3	-0.3	-0.1	0.5	
5	13.7	-0.1	-0.1	0.1	0.3	
6	13.6	-0.1	-0.3	-0.1	0.1	
7	15.3	-1.7	-1.6	-1.6	0.1	
8	14.5	-0.5	-0.8	-0.5	0.7	
9	14.8	-0.9	-1.0	-0.8	1.0	
10	14.5	-0.3	-0.4	-0.1	0.7	
11	14.6	-0.6	-0.9	-0.7	1.0	
12	15.1	-0.3	-0.9	-0.6	0.8	
13	14.8	-0.8	-0.9	-0.8	-0.8	
14	15.1	-1.0	-1.5	-1.1	0.0	
15	15.3	-0.6	-1.2	-1.0	1.2	
16	14.4	-0.6	-0.8	-0.7	0.7	
17	15.0	-0.7	-1.5	-1.2	-0.1	
18	14.7	-0.4	-0.8	-0.6	0.6	
19	15.5	-1.1	-1.9	-1.6	-0.9	
20	13.3	0.5	0.1	0.4	0.7	
21	13.6	-0.2	-0.4	-0.2	0.4	
22	13.3	0.2	0.0	0.2	1.1	
23	13.7	-0.2	-0.2	-0.1	0.2	
24	13.2	0.1	0.1	0.1	0.7	
25	13.5	0.0	0.0	-0.1	0.4	
MAX	15.6	0.5	0.1	0.4	1.2	
MIN	13.2	-1.7	-1.9	-1.6	-0.9	
AVG	14.3	-0.4	-0.7	-0.5	0.4	
STD	0.8	0.5	0.6	0.6	0.5	
Open	0	0	0	0	0	
Tech	LL	MHB	LL	S.Rath	S.Rath	
Equip ID	1047	1276	1047	1032	1032	
	476	207	476	1546	1546	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A 50Au				File #:	20914528
Description:	50 Au				Sample ID:	28
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	14.1	0.0	0.0	-0.1	0.5	
2	13.3	-0.3	-0.1	-0.2	0.3	
3	13.3	0.1	0.0	-0.1	0.4	
4	13.5	-0.3	-0.3	-0.4	-0.2	
5	13.2	-0.1	-0.2	-0.3	0.2	
6	13.1	0.2	0.0	-0.1	0.4	
7	15.1	-1.4	-1.2	-1.5	-0.6	
8	15.2	-2.1	-1.9	-1.8	-0.8	
9	15.1	-1.8	-1.5	-1.8	-0.8	
10	15.5	-2.0	-1.9	-2.1	-1.4	
11	14.7	-1.1	-0.7	-0.7	0.4	
12	14.5	-0.7	-0.5	-0.6	0.2	
13	14.2	-0.7	-0.5	-0.7	-0.2	
14	15.3	-1.5	-1.2	-1.3	-0.2	
15	14.6	-1.6	-1.3	-1.4	-0.9	
16	14.9	-1.6	0.1	-1.7	-0.9	
17	14.7	-1.6	-1.5	-1.7	-1.1	
18	14.2	-1.1	-1.0	-1.0	-0.1	
19	15.0	-1.9	-1.8	-1.9	-0.9	
20	13.2	0.0	0.0	-0.2	0.5	
21	13.3	-0.1	-0.1	-0.2	0.5	
22	13.3	0.1	0.0	-0.2	0.5	
23	13.3	-0.2	-0.1	-0.2	0.1	
24	13.3	-0.2	-0.1	-0.2	0.1	
25	13.2	0.3	0.0	-0.8	0.0	

					File #:	20914528
			Delta values			
			units: milliohms			
MAX	15.5	0.3	0.1	-0.1	0.5	
MIN	13.1	-2.1	-1.9	-2.1	-1.4	
AVG	14.1	-0.8	-0.6	-0.9	-0.2	
STD	0.8	0.8	0.7	0.7	0.6	
Open	0	0	0	0	0	
Tech	LL	MHB	LL	S.Rath	S.Rath	
Equip ID	1047	1276	1047	1546	1546	
	476	207	476	1032	1032	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A 50Au				File #:	20914529
Description:	50 Au				Sample ID:	29
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.5	-0.4	-0.1	-0.2	0.1	
2	13.4	-0.6	0.4	0.1	0.4	
3	13.6	-0.5	0.4	-0.1	0.2	
4	13.5	-0.6	0.4	0.1	0.2	
5	13.5	-0.5	0.3	0.0	0.3	
6	13.4	-0.5	0.0	-0.1	0.3	
7	14.1	-1.0	-0.6	-0.6	0.5	
8	14.0	-1.2	-0.9	-1.0	0.2	
9	13.9	-0.8	-0.6	-0.4	1.3	
10	14.4	-1.0	0.7	-0.1	-0.1	
11	14.4	-0.9	-0.5	-0.8	0.6	
12	16.6	-3.3	-2.9	-3.2	-1.7	
13	14.3	-1.0	-0.3	-0.8	0.3	
14	14.1	-0.9	-0.1	-0.6	1.1	
15	15.1	-0.9	-0.1	-0.6	0.6	
16	14.0	-0.6	1.2	0.3	0.1	
17	14.2	-0.9	-0.3	-0.8	0.5	
18	14.3	-1.0	0.0	-0.6	0.3	
19	15.6	-1.4	-1.2	-1.4	-1.0	
20	13.6	-0.5	-0.2	-0.4	0.0	
21	13.4	-0.2	0.1	-0.1	0.3	
22	13.5	-0.5	0.0	-0.2	0.1	
23	13.6	-0.6	-0.3	-0.4	0.0	
24	13.5	-0.4	-0.1	-0.3	0.2	
25	14.0	-0.7	-0.4	-0.6	-0.4	

					File #:	20914529
			Delta values			
			units: milliohms			
MAX	16.6	-0.2	1.2	0.3	1.3	
MIN	13.4	-3.3	-2.9	-3.2	-1.7	
AVG	14.1	-0.8	-0.2	-0.5	0.2	
STD	0.8	0.6	0.8	0.7	0.6	
Open	0	0	0	0	0	
Tech	LL	MHB	LL	S.Rath	S.Rath	
Equip ID	1047	1276	1047	1032	1032	
	476	207	476	1546	1546	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-170-01-C-DV-A 50Au				File #:	20914530
Description:	50 Au				Sample ID:	30
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.8	-0.5	-0.4	-0.5	0.1	
2	13.8	-0.8	-0.7	-0.7	0.6	
3	13.6	-0.7	-0.6	-0.7	0.0	
4	13.6	-0.6	-0.5	-0.6	0.0	
5	13.5	-0.6	-0.6	-0.7	-0.1	
6	13.4	-0.4	-0.4	-0.4	0.1	
7	14.8	-1.6	-1.5	0.1	1.2	
8	13.6	-0.7	-0.4	-0.4	0.9	
9	14.7	-1.5	-1.3	-1.2	0.0	
10	14.8	-1.6	-1.3	-1.1	0.5	
11	14.3	-1.1	-0.9	-1.0	1.5	
12	14.0	-0.8	-0.5	-0.6	1.0	
13	14.6	-1.1	-1.0	-1.3	0.6	
14	14.0	-1.0	-0.7	-0.8	-0.5	
15	15.0	-1.7	-1.5	-1.6	-0.6	
16	14.0	-1.0	-0.7	-1.4	0.0	
17	14.4	-1.1	-0.7	-0.9	1.2	
18	13.9	-0.9	-0.6	-0.9	0.8	
19	15.1	-1.9	-1.7	-1.5	0.4	
20	13.4	-0.5	-0.4	-0.5	0.5	
21	13.5	-0.5	-0.4	-0.4	-0.1	
22	13.4	-0.3	-0.3	-0.3	0.3	
23	13.3	-0.2	-0.2	-0.1	0.4	
24	13.3	-0.2	-0.2	-0.1	0.4	
25	13.7	-0.6	-0.5	-0.2	0.2	
MAX	15.1	-0.2	-0.2	0.1	1.5	
MIN	13.3	-1.9	-1.7	-1.6	-0.6	
AVG	14.0	-0.9	-0.7	-0.7	0.4	
STD	0.6	0.5	0.4	0.5	0.5	
Open	0	0	0	0	0	
Tech	LL	MHB	LL	S.Rath	S.Rath	
Equip ID	1047	1276	1047	1032	1032	
	476	207	476	1546	1546	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MEC8-120-01-C-DV-A 50Au				File #:	20914531
Description:	50 Au				Sample ID:	31
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.5	-0.2	-0.2	-0.3	0.0	
2	13.5	-0.4	-0.5	-0.6	0.2	
3	13.2	-0.2	-0.3	-0.3	0.1	
4	13.5	-0.3	-0.3	-0.3	0.0	
5	13.4	-0.2	-0.2	-0.3	0.1	
6	13.7	-0.6	-0.5	-0.5	0.0	
7	13.8	-0.1	-0.1	-0.2	1.7	
8	14.1	-0.5	-0.6	-0.6	0.1	
9	14.1	-0.3	-0.5	-0.5	1.0	
10	14.2	-0.2	-0.2	-0.3	1.4	
11	13.9	0.1	0.0	0.0	0.8	
12	14.0	-0.2	-0.1	-0.2	0.9	
13	13.9	-0.1	-0.1	-1.0	0.9	
14	14.0	-0.2	-0.4	-0.5	0.5	
15	13.9	0.0	-0.3	-0.4	0.4	
16	13.9	-0.3	-0.2	-0.4	0.3	
17	13.9	0.0	-0.3	-0.4	0.3	
18	13.9	0.1	-0.1	-0.3	0.4	
19	13.9	-0.2	-0.1	-0.4	1.5	
20	13.6	-0.1	-0.2	-0.3	0.2	
21	13.6	-0.1	-0.2	-0.2	0.2	
22	13.4	-0.2	-0.2	-0.3	0.1	
23	13.4	-0.1	-0.3	-0.3	0.0	
24	13.3	-0.2	-0.2	-0.2	-0.1	
25	13.5	-0.3	-0.3	-0.3	-0.1	
MAX	14.2	0.1	0.0	0.0	1.7	
MIN	13.2	-0.6	-0.6	-1.0	-0.1	
AVG	13.7	-0.2	-0.3	-0.4	0.4	
STD	0.3	0.2	0.1	0.2	0.5	
Open	0	0	0	0	0	
Tech	LL	MHB	LL	S.Rath	S.Rath	
Equip ID	1047	1276	1047	1546	1546	
	476	207	476	1032	1032	

Low Level Contact Resistance						
Project:	209145				Spec:	EIA 364, TP23
Customer:	Samtec				Subgroup:	N/A
Product:	MECA-120-01-C-DV-A 50Au				File #:	20914532
Description:	50 Au				Sample ID:	32
Open circuit voltage:		20mv			Current:	100ma
			Delta values			
			units: milliohms			
Temp ºC	22	20	22	20	20	
R.H. %	24	31	26	34	34	
Date:	17Mar09	02Apr09	13Apr09	21Apr09	21Apr09	
Pos. ID	Initial	T.Life	7D MFG	14D MFG	1X	
1	13.6	-0.3	0.0	0.2	-0.2	
2	13.3	0.0	0.2	0.4	0.5	
3	13.3	-0.1	0.0	0.1	0.2	
4	13.3	-0.1	0.1	0.3	0.1	
5	13.2	0.0	0.0	0.3	0.0	
6	13.2	-0.2	-0.1	0.2	0.6	
7	14.6	-1.5	-1.5	-1.0	-1.4	
8	13.9	-1.1	-1.1	-0.9	-0.5	
9	14.0	-1.0	-1.1	-0.7	-0.4	
10	14.4	-1.2	-1.4	-1.1	-0.6	
11	14.2	-1.1	-1.1	-0.7	-0.7	
12	13.9	-0.7	-0.7	-0.5	-0.3	
13	13.8	-0.8	-0.8	-0.4	-0.1	
14	14.2	-1.0	-1.0	-0.6	0.0	
15	14.6	-1.3	-1.3	-0.9	-2.1	
16	14.2	-1.1	-1.0	-0.7	-0.5	
17	14.5	-1.3	-1.3	-0.9	-0.5	
18	14.2	-1.1	-0.9	-0.5	-0.7	
19	14.6	-1.6	-1.5	-1.1	-1.3	
20	13.1	0.0	0.0	0.1	0.2	
21	13.3	-0.1	-0.2	0.1	0.3	
22	13.0	0.3	0.2	0.3	0.6	
23	13.3	0.1	0.1	0.2	0.4	
24	13.3	0.2	0.0	0.1	0.5	
25	13.3	0.2	0.1	0.4	0.4	
MAX	14.6	0.3	0.2	0.4	0.6	
MIN	13.0	-1.6	-1.5	-1.1	-2.1	
AVG	13.8	-0.6	-0.6	-0.3	-0.2	
STD	0.5	0.6	0.6	0.5	0.7	
Open	0	0	0	0	0	
Tech	LL	MHB	LL	S.Rath	S.Rath	
Equip ID	1047	1276	1047	1032	1032	
	476	207	476	1546	1546	